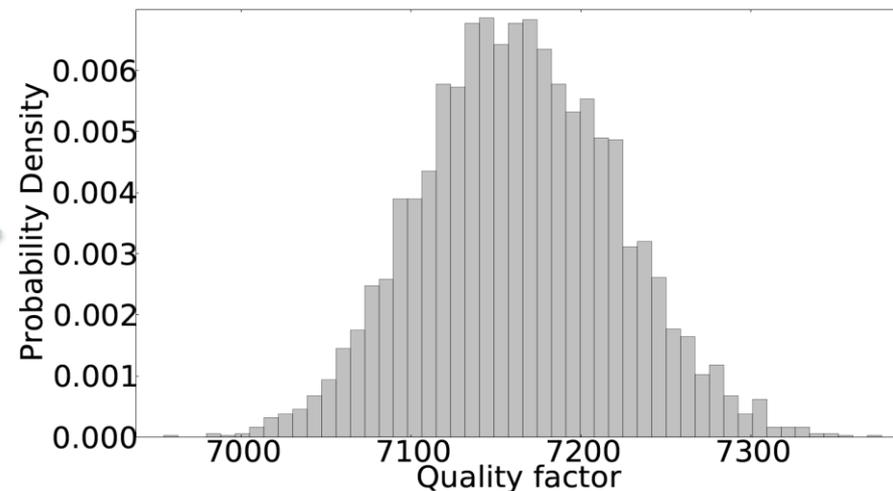
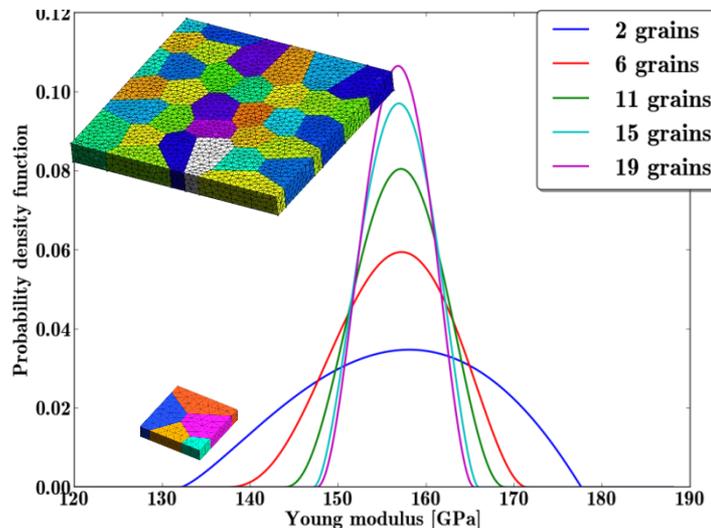


A stochastic 3-scale method for polycrystalline materials

*Wu Ling, Lucas Vincent, Golinval Jean-Claude,
Paquay Stéphane, Noels Ludovic*



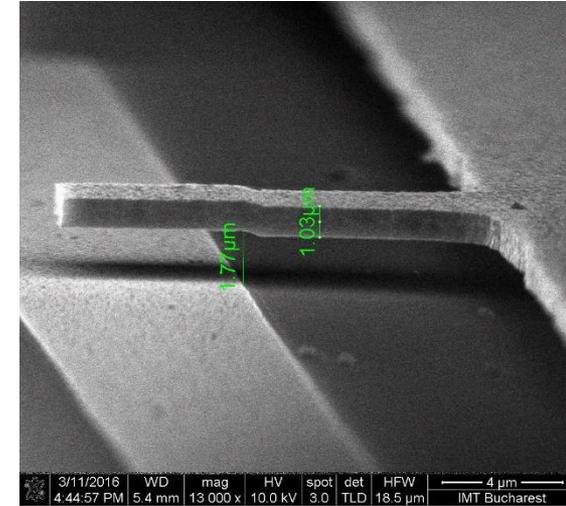
3SMVIB: The research has been funded by the Walloon Region under the agreement no 1117477 (CT-INT 2011-11-14) in the context of the ERA-NET MNT framework. Experimental measurements provided by IMT Bucharest (Voicu Rodica, Baracu Angela, Muller Raluca)

The problem

- MEMS structures

- Are not several orders larger than their micro-structure size
- Parameters-dependent manufacturing process
 - Low Pressure Chemical Vapor Deposition (LPCVD)
 - Properties depend on the temperature, time process, and flow gas conditions
- Scatter in the structural properties
 - Due to the fabrication process (photolithography, etching ...)
 - Due to uncertainties of the material
 - ...

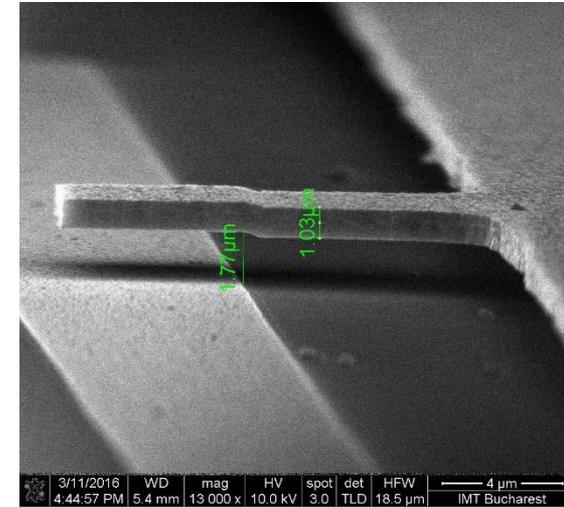
→ The objective of this work is to estimate this scatter



The problem

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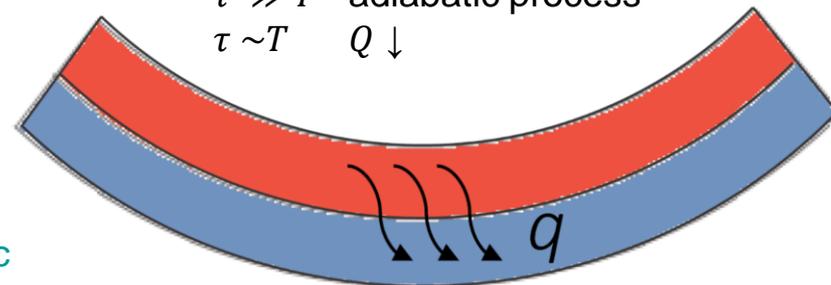


→ The objective of this work is to estimate this scatter

- Application example

- Poly-silicon resonators
- Quantities of interest
 - Eigen frequency
 - Quality factor due to thermoelastic damping $Q \sim W/\Delta W$
 - Thermoelastic damping is a source of intrinsic material damping present in almost all materials

$\tau \ll T$ isothermal process
 $\tau \gg T$ adiabatic process
 $\tau \sim T$ $Q \downarrow$

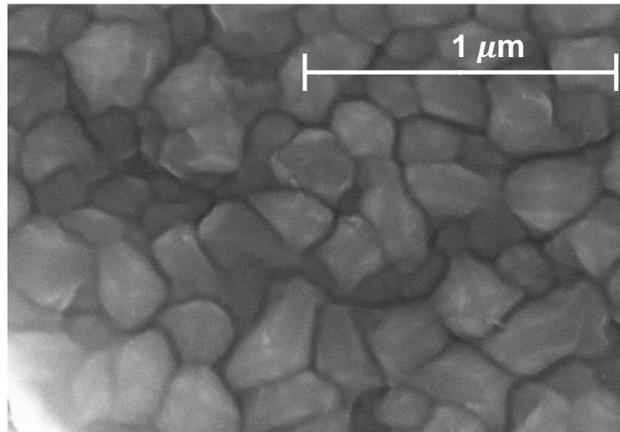


The problem

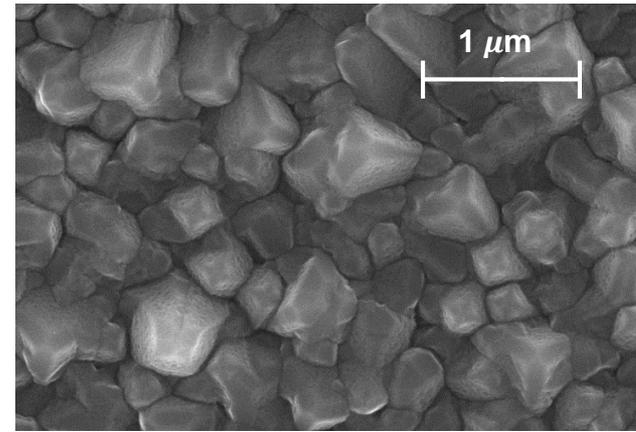
- Material structure: grain size distribution

SEM Measurements (Scanning Electron Microscope)

- Grain size dependent on the LPCVD temperature process
- 2 μm -thick poly-silicon films



Deposition temperature: 580 °C



Deposition temperature: 650 °C

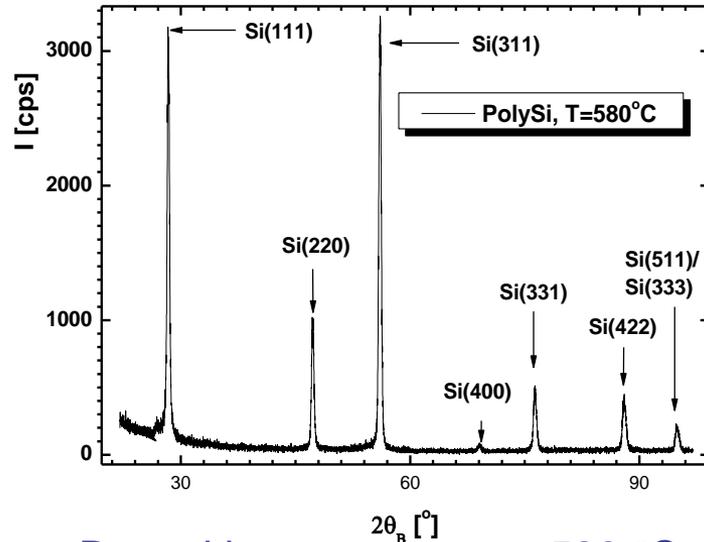
Deposition temperature [°C]	580	610	630	650
Average grain diameter [μm]	0.21	0.45	0.72	0.83

SEM images provided by IMT Bucharest, Rodica Voicu, Angela Baracu, Raluca Muller

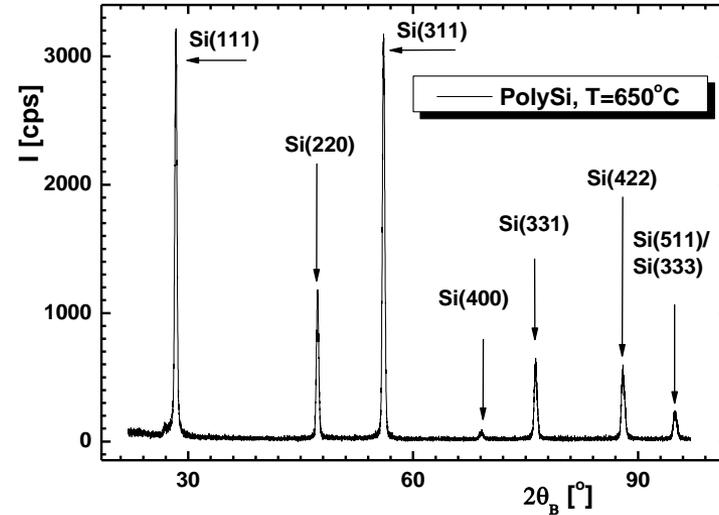
The problem

- Material structure: grain orientation distribution

- Grain orientation by XRD (X-ray Diffraction) measurements on 2 μm -thick poly-silicon films



Deposition temperature: 580 °C



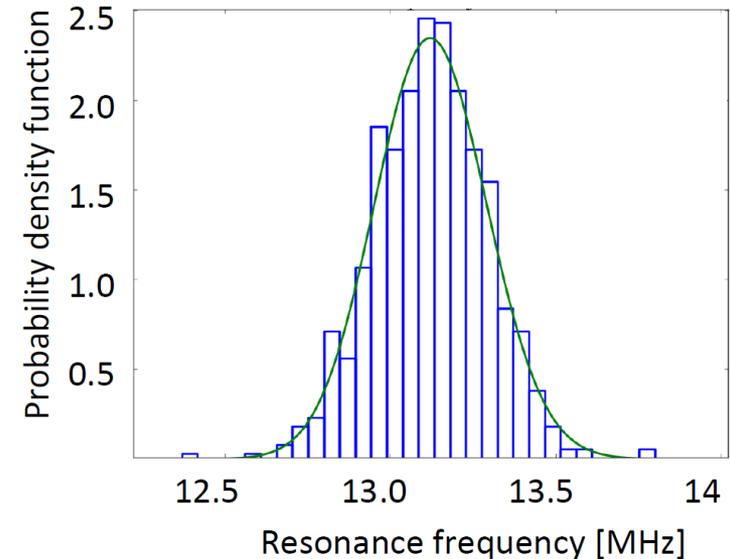
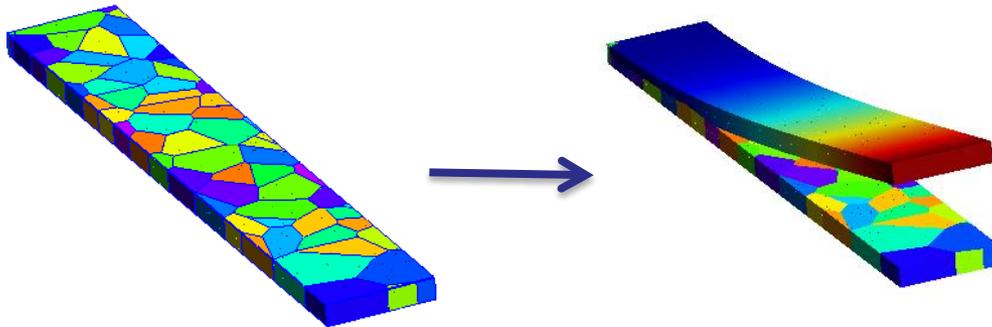
Deposition temperature: 630 °C

Deposition temperature [°C]	580	610	630	650
$\langle 111 \rangle$ [%]	12.57	19.96	12.88	11.72
$\langle 220 \rangle$ [%]	7.19	13.67	7.96	7.59
$\langle 311 \rangle$ [%]	42.83	28.83	39.08	38.47
$\langle 400 \rangle$ [%]	4.28	5.54	3.13	3.93
$\langle 331 \rangle$ [%]	17.97	18.14	21.32	20.45
$\langle 422 \rangle$ [%]	15.15	13.86	15.63	17.84

XRD images provided by IMT Bucharest, Rodica Voicu, Angela Baracu, Raluca Muller

Monte-Carlo for a fully modelled beam

- The first mode frequency distribution can be obtained with
 - A 3D beam with each grain modelled
 - Grains distribution according to experimental measurements
 - Monte-Carlo simulations

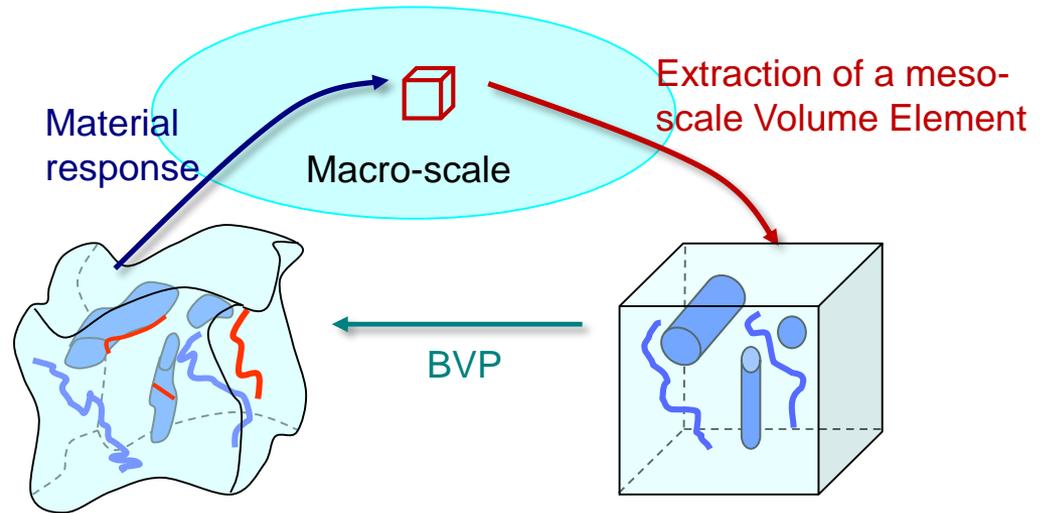


- Considering each grain is expensive and time consuming
 - ↳ Motivation for stochastic multi-scale methods

Motivations

- Multi-scale modelling

- 2 problems are solved concurrently
 - The macro-scale problem
 - The meso-scale problem (on a meso-scale Volume Element)



- Length-scales separation

$$L_{\text{macro}} \gg L_{\text{VE}} \gg L_{\text{micro}}$$

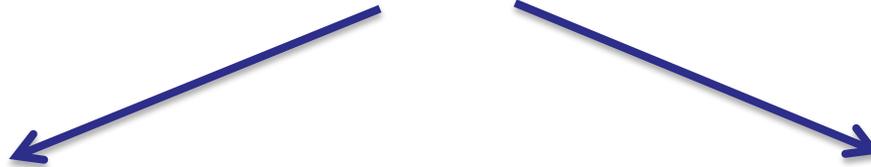
For accuracy: Size of the meso-scale volume element smaller than the characteristic length of the macro-scale loading

To be statistically representative: Size of the meso-scale volume element larger than the characteristic length of the micro-structure

Motivations

- For structures not several orders larger than the micro-structure size

$$L_{\text{macro}} \gg L_{\text{VE}} \sim L_{\text{micro}}$$



For accuracy: Size of the meso-scale volume element smaller than the characteristic length of the macro-scale loading

Meso-scale volume element no longer statistically representative: Stochastic Volume Elements*

- Possibility to propagate the uncertainties from the micro-scale to the macro-scale

*M Ostoja-Starzewski, X Wang, 1999

P Trovalusci, M Ostoja-Starzewski, M L De Bellis, A Murralli, 2015

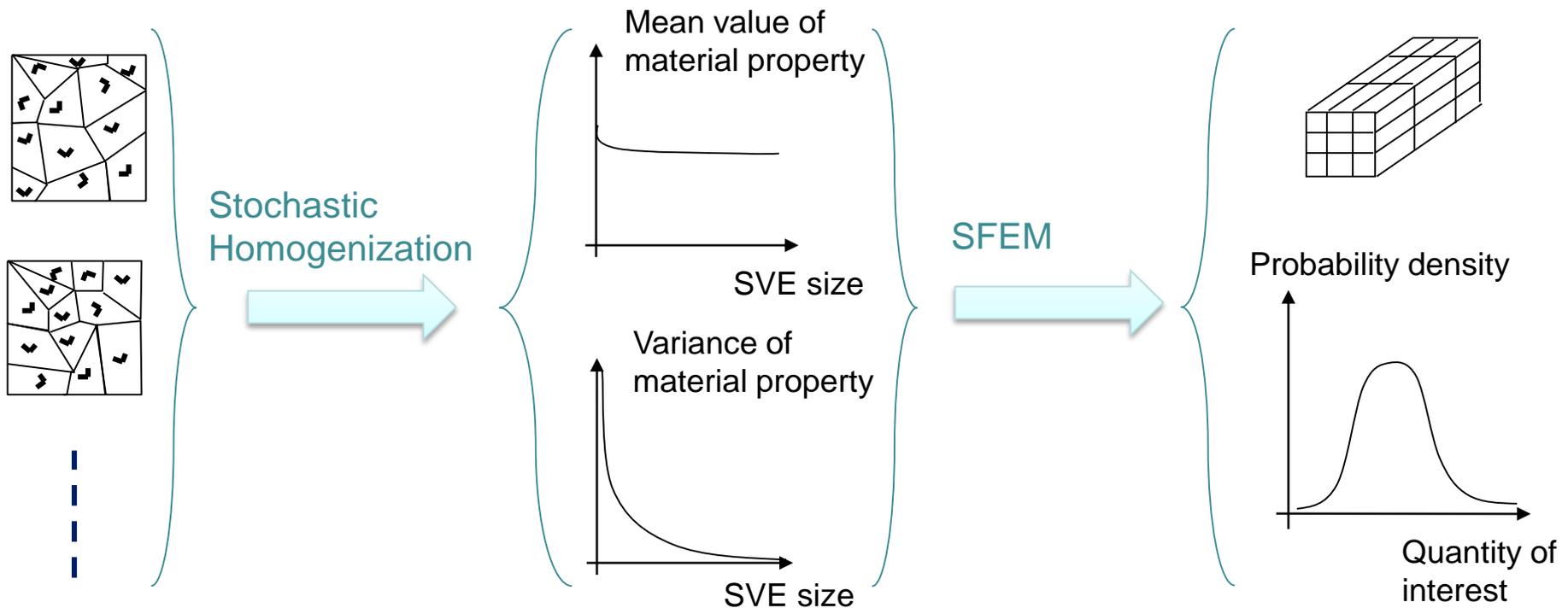
X. Yin, W. Chen, A. To, C. McVeigh, 2008

J. Guillemot, A. Noshadravan, C. Soize, R. Ghanem, 2011

....

A 3-scale process

Grain-scale or micro-scale	Meso-scale	Macro-scale
<ul style="list-style-type: none"> ➤ Samples of the microstructure (volume elements) are generated ➤ Each grain has a random orientation 	<ul style="list-style-type: none"> ➤ Intermediate scale ➤ The distribution of the material property $\mathbb{P}(C)$ is defined 	<ul style="list-style-type: none"> ➤ Uncertainty quantification of the macro-scale quantity ➤ E.g. the first mode frequency $\mathbb{P}(f_1)$ /Quality factor $\mathbb{P}(Q)$



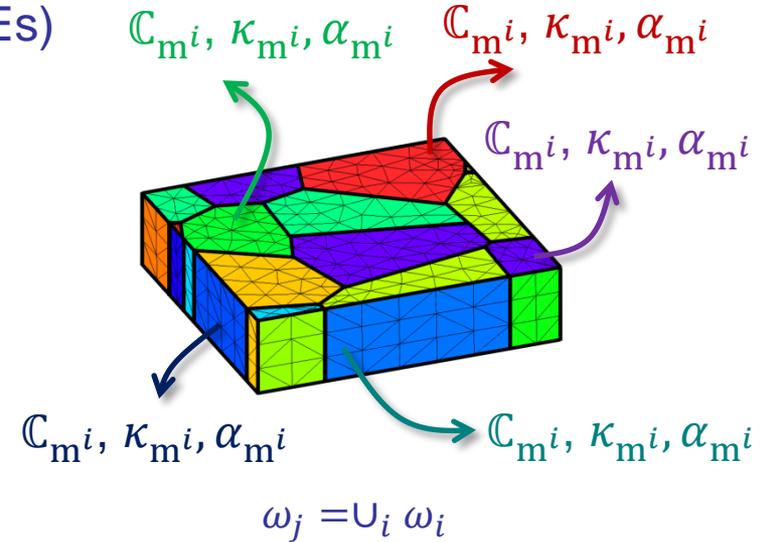
- **From the micro-scale to the meso-scale**
 - Thermo-mechanical homogenization
 - Definition of Stochastic Volume Elements (SVEs) & Stochastic homogenization
 - Need for a meso-scale random field
- **The meso-scale random field**
 - Definition of the thermo-mechanical meso-scale random field
 - Stochastic model of the random field: Spectral generator & non-Gaussian mapping
- **From the meso-scale to the macro-scale**
 - 3-Scale approach verification
 - Application to extract the quality factor
- **Accounting for roughness effect**
 - From the micro-scale to the meso-scale
 - The meso-scale random field
 - From the meso-scale to the macro-scale

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From the micro-scale to the meso-scale

- Definition of Stochastic Volume Elements (SVEs)

- Poisson Voronoï tessellation realizations
 - SVE realization ω_j
- Each grain ω_i is assigned material properties
 - Elasticity tensor \mathbb{C}_{m^i} ;
 - Heat conductivity tensor κ_{m^i} ;
 - Thermal expansion tensors α_{m^i} .
 - Defined from silicon crystal properties
- Each set $\mathbb{C}_{m^i}, \kappa_{m^i}, \alpha_{m^i}$ is assigned a random orientation
 - Following XRD distributions



- Stochastic homogenization

- Several SVE realizations
- For each SVE $\omega_j = U_i \omega_i$

$$\mathbb{C}_{m^i}, \kappa_{m^i}, \alpha_{m^i} \quad \forall i$$



Computational homogenization

$$\mathbb{C}_{Mj}, \kappa_{Mj}, \alpha_{Mj}$$

Samples of the meso-scale homogenized elasticity tensors

- Homogenized material tensors not unique as statistical representativeness is lost*

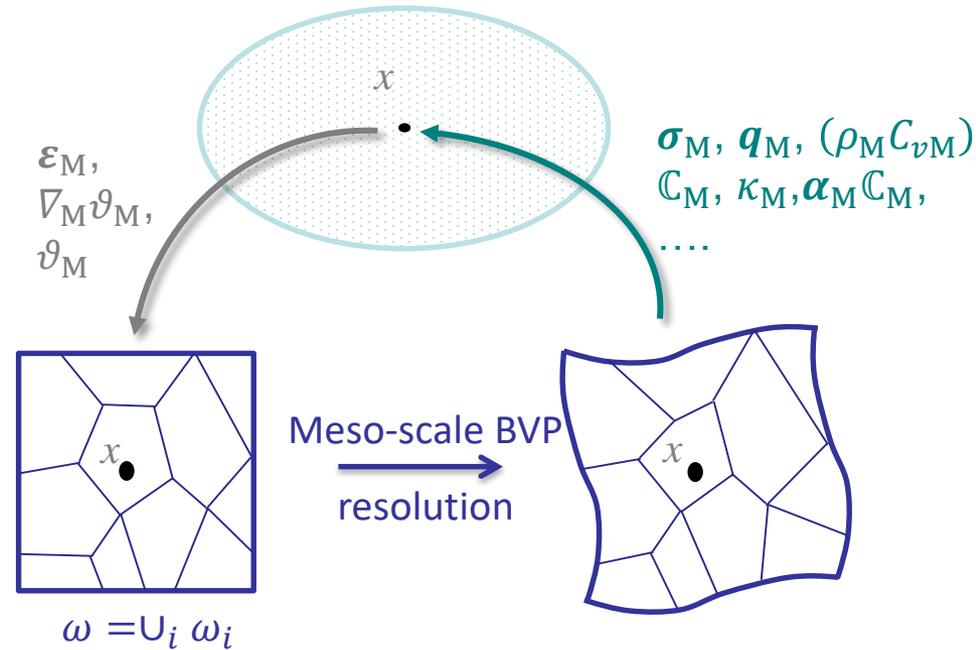
*C. Huet, 1990

From the micro-scale to the meso-scale

- Thermo-mechanical homogenization

- Down-scaling

$$\left\{ \begin{array}{l} \boldsymbol{\varepsilon}_M = \frac{1}{V(\omega)} \int_{\omega} \boldsymbol{\varepsilon}_m d\omega \\ \nabla_M \vartheta_M = \frac{1}{V(\omega)} \int_{\omega} \nabla_m \vartheta_m d\omega \\ \vartheta_M = \frac{1}{V(\omega)} \int_{\omega} \frac{\rho_m C_{vm}}{\rho_M C_{vM}} \vartheta_m d\omega \end{array} \right.$$



- Up-scaling

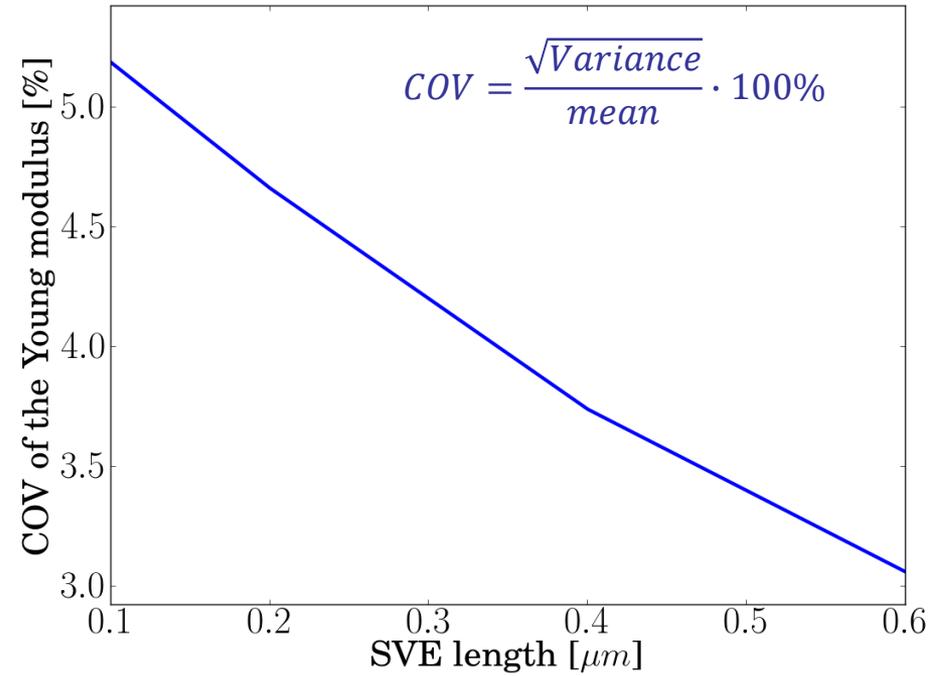
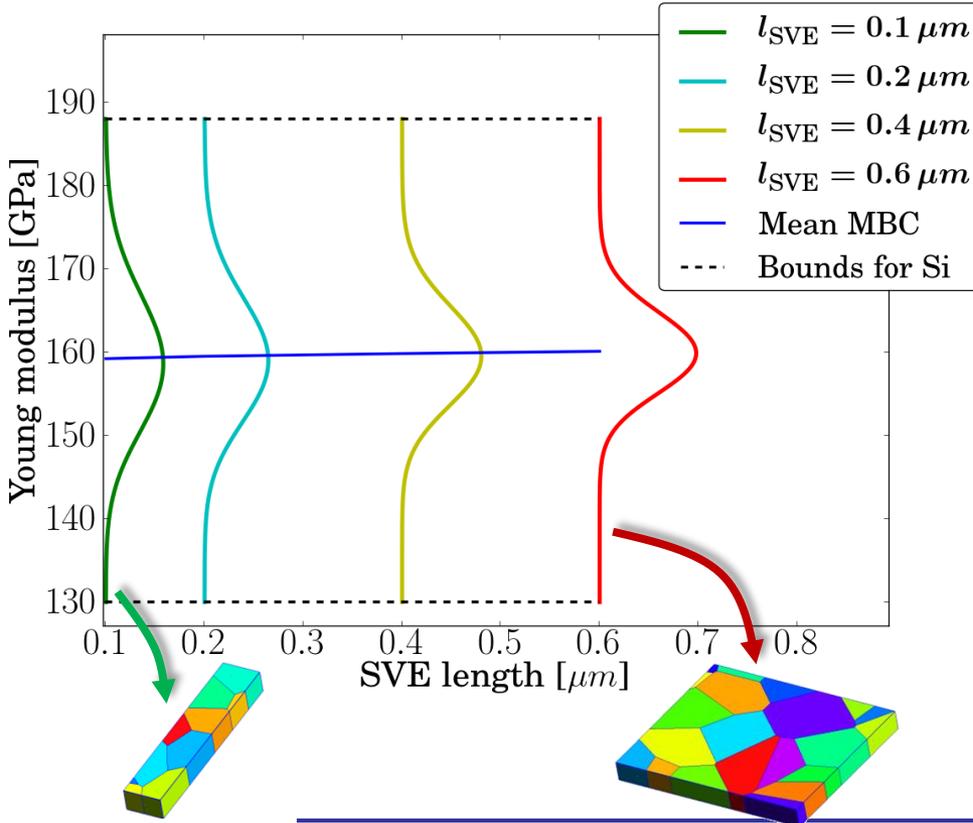
$$\left\{ \begin{array}{l} \boldsymbol{\sigma}_M = \frac{1}{V(\omega)} \int_{\omega} \boldsymbol{\sigma}_m d\omega \\ \mathbf{q}_M = \frac{1}{V(\omega)} \int_{\omega} \mathbf{q}_m d\omega \\ \rho_M C_{vM} = \frac{1}{V(\omega)} \int_{\omega} \rho_m C_{vm} dV \end{array} \right. \longrightarrow \left\{ \begin{array}{l} \mathbb{C}_M = \frac{\partial \boldsymbol{\sigma}_M}{\partial \mathbf{u}_M \otimes \nabla_M} \quad \& \quad \boldsymbol{\alpha}_M : \mathbb{C}_M = - \frac{\partial \boldsymbol{\sigma}_M}{\partial \vartheta_M} \\ \kappa_M = - \frac{\partial \mathbf{q}_M}{\partial \nabla_M \vartheta_M} \end{array} \right.$$

- Consistency \longrightarrow Satisfied by periodic boundary conditions

From the micro-scale to the meso-scale

- Distribution of the apparent meso-scale elasticity tensor \mathbb{C}_M

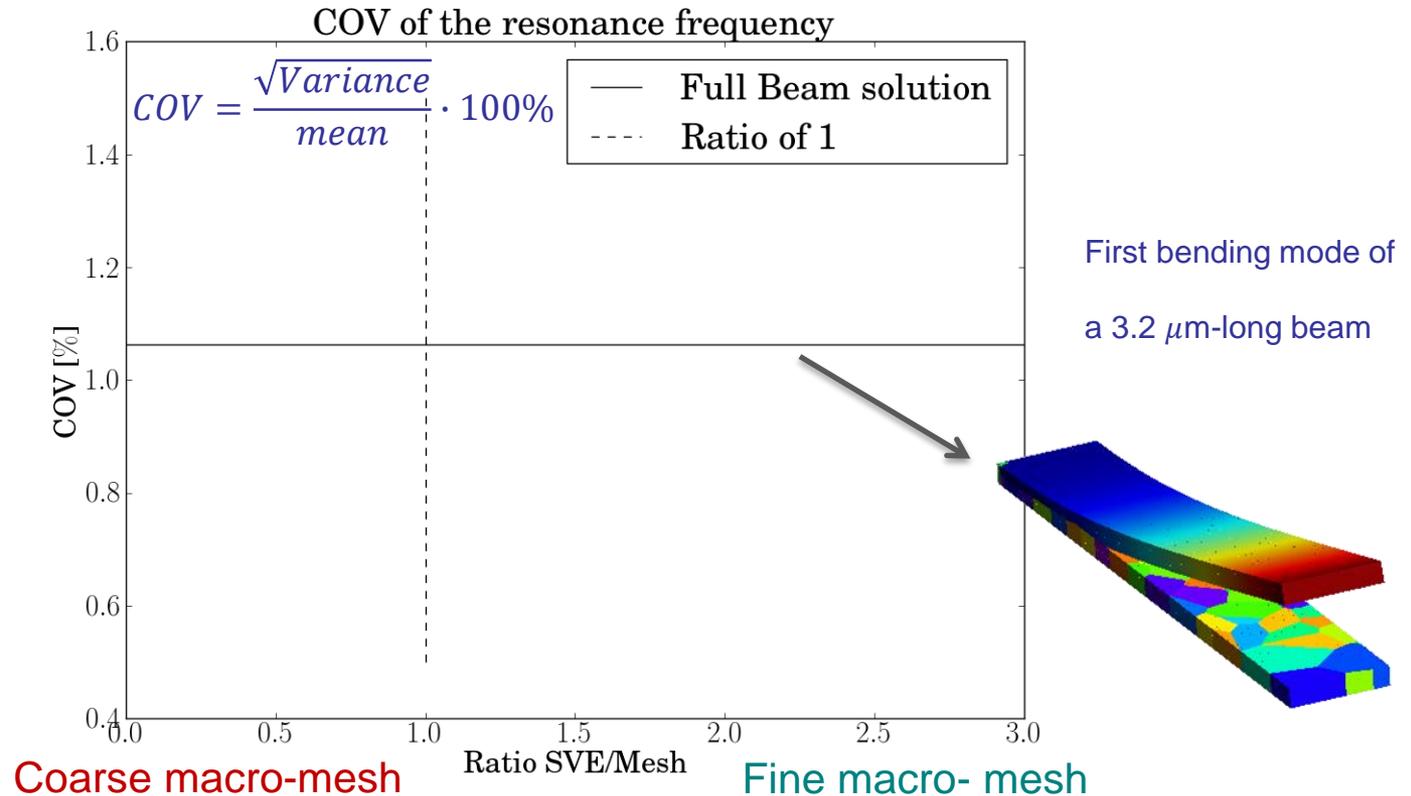
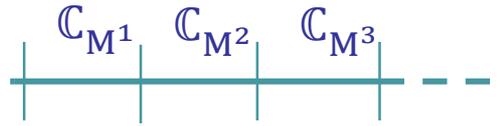
➤ For large SVEs, the apparent tensor tends to the effective (and unique) one



- The bounds do not depend on the SVE size but on the silicon elasticity tensor
- However, the larger the SVE, the lower the probability to be close to the bounds

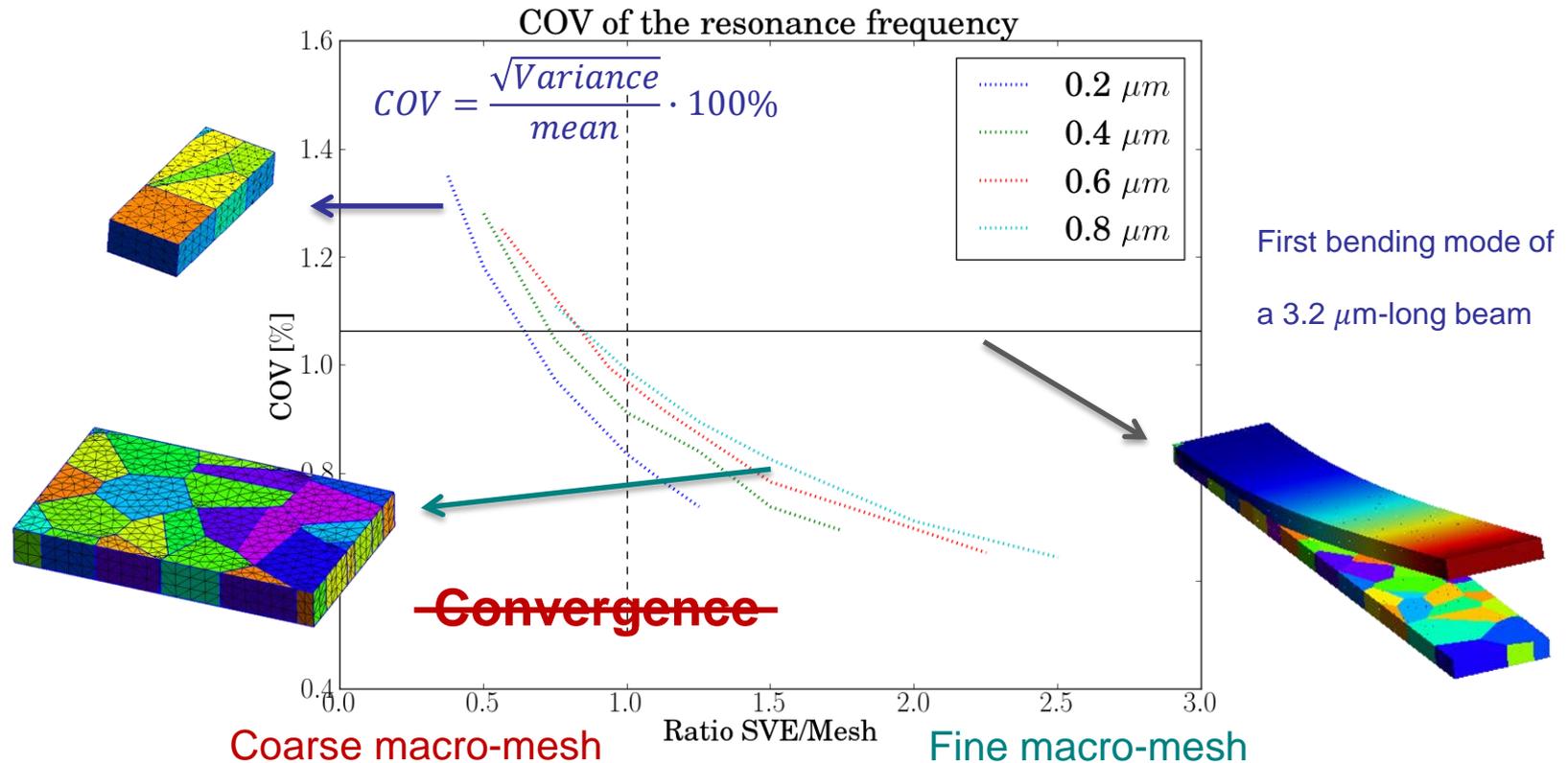
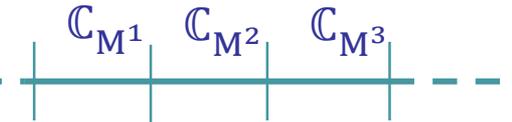
From the micro-scale to the meso-scale

- Use of the meso-scale distribution with macro-scale finite elements
 - Beam macro-scale finite elements
 - Use of the meso-scale distribution as a random variable
 - Monte-Carlo simulations



From the micro-scale to the meso-scale

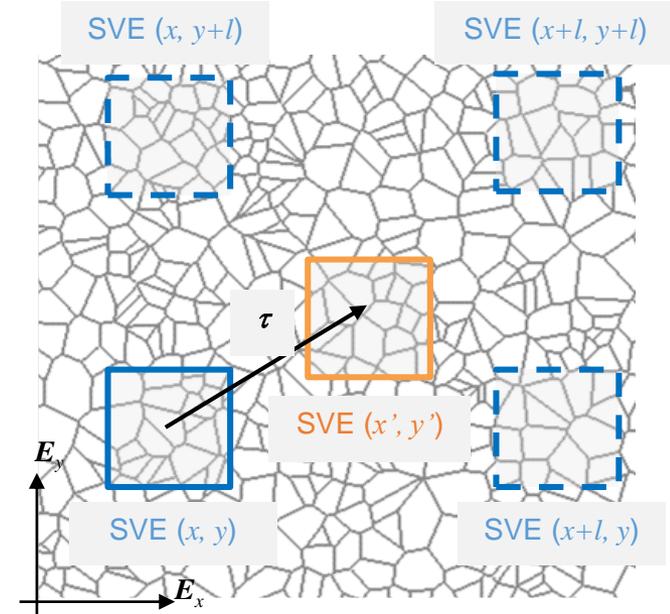
- Use of the meso-scale distribution with macro-scale finite elements
 - Beam macro-scale finite elements
 - Use of the meso-scale distribution as a random variable
 - Monte-Carlo simulations



- No convergence: the macro-scale distribution (first resonance frequency) depends on SVE and mesh sizes

From the micro-scale to the meso-scale

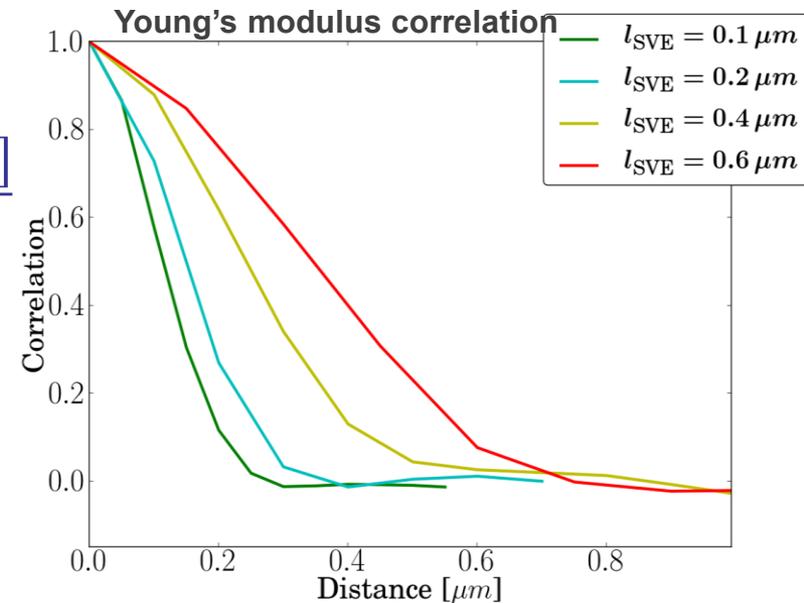
- Need for a meso-scale random field
 - Introduction of the (meso-scale) spatial correlation
 - Define large tessellations
 - SVEs extracted at different distances in each tessellation
 - Evaluate the spatial correlation between the components of the meso-scale material operators
 - For example, in 1D-elasticity
 - Young's modulus correlation



$$R_{E_x}(\tau) = \frac{\mathbb{E}[(E_x(x) - \mathbb{E}(E_x))(E_x(x + \tau) - \mathbb{E}(E_x))]}{\mathbb{E}[(E_x - \mathbb{E}(E_x))^2]}$$

- Correlation length

$$L_{E_x} = \frac{\int_{-\infty}^{\infty} R_{E_x}(\tau) d\tau}{R_{E_x}(0)}$$



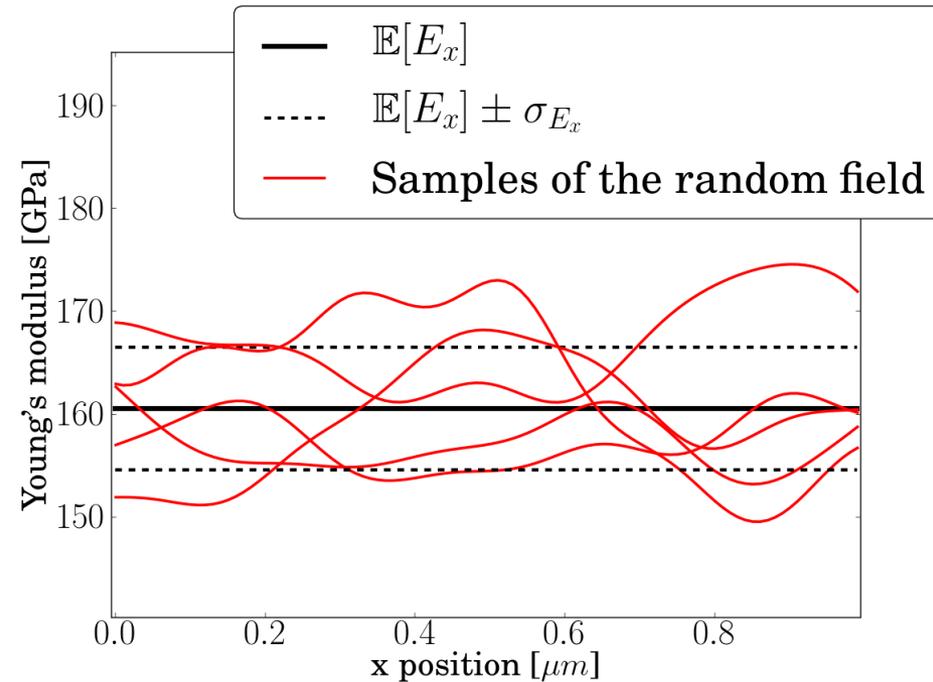
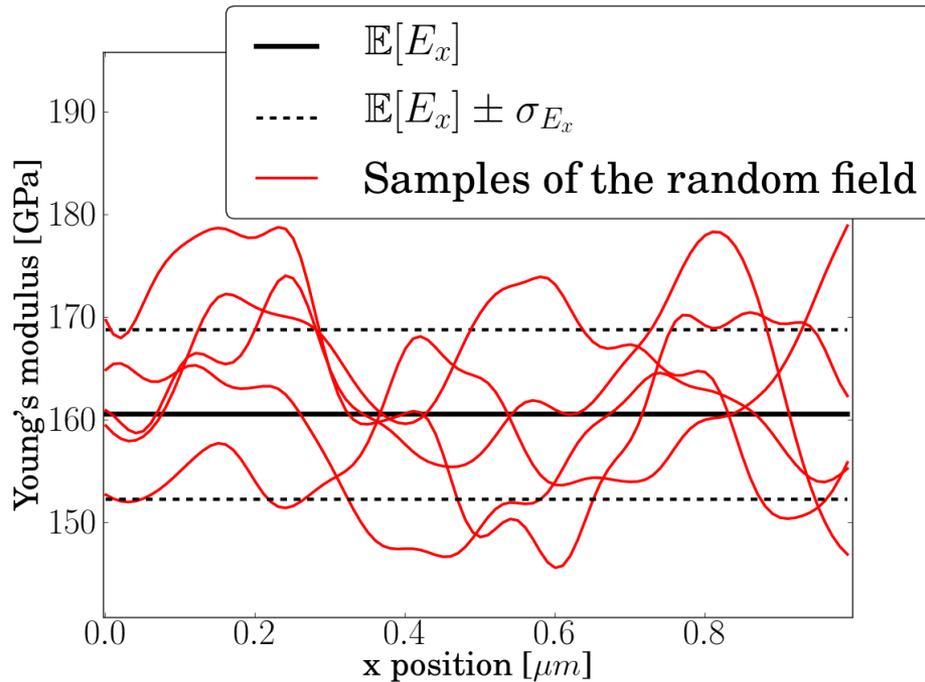
From the micro-scale to the meso-scale

- Need for a meso-scale random field (2)
 - The meso-scale random field is characterized by the correlation length L_{E_x}
 - The correlation length L_{E_x} depends on the SVE size

Random field with different SVEs sizes

$l_{SVE} = 0.1 \mu m$

$l_{SVE} = 0.4 \mu m$



From the micro-scale to the meso-scale

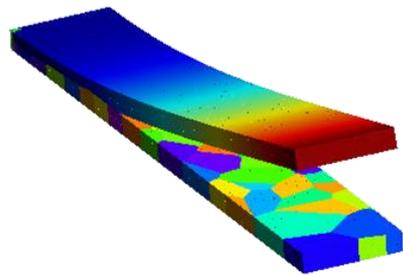
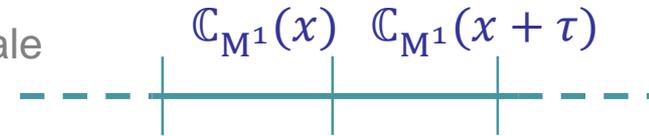
- Need for a meso-scale random field (3)

- Use of the meso-scale random field

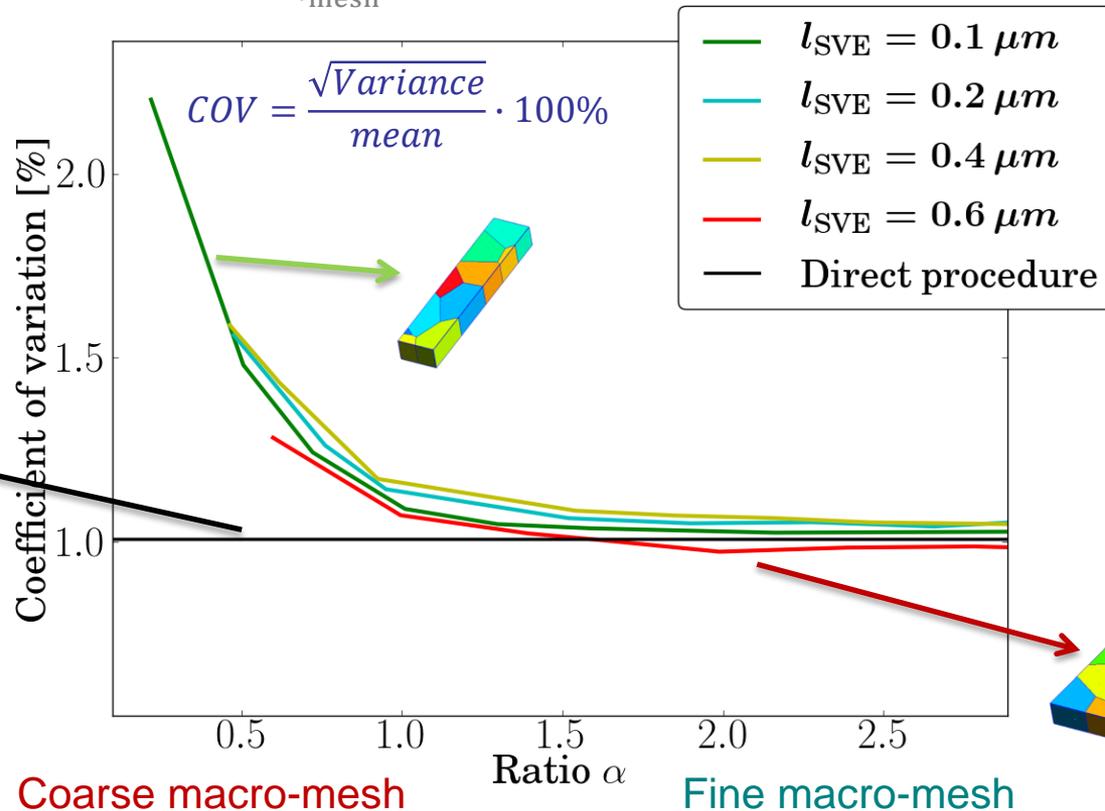
- Monte-Carlo simulations at the macro-scale

- Macro-scale beam elements of size l_{mesh}

- Convergence in terms of $\alpha = \frac{L_{Ex}}{l_{\text{mesh}}}$

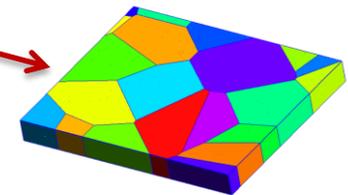


First bending mode of a $3.2 \mu\text{m}$ -long beam



Coarse macro-mesh

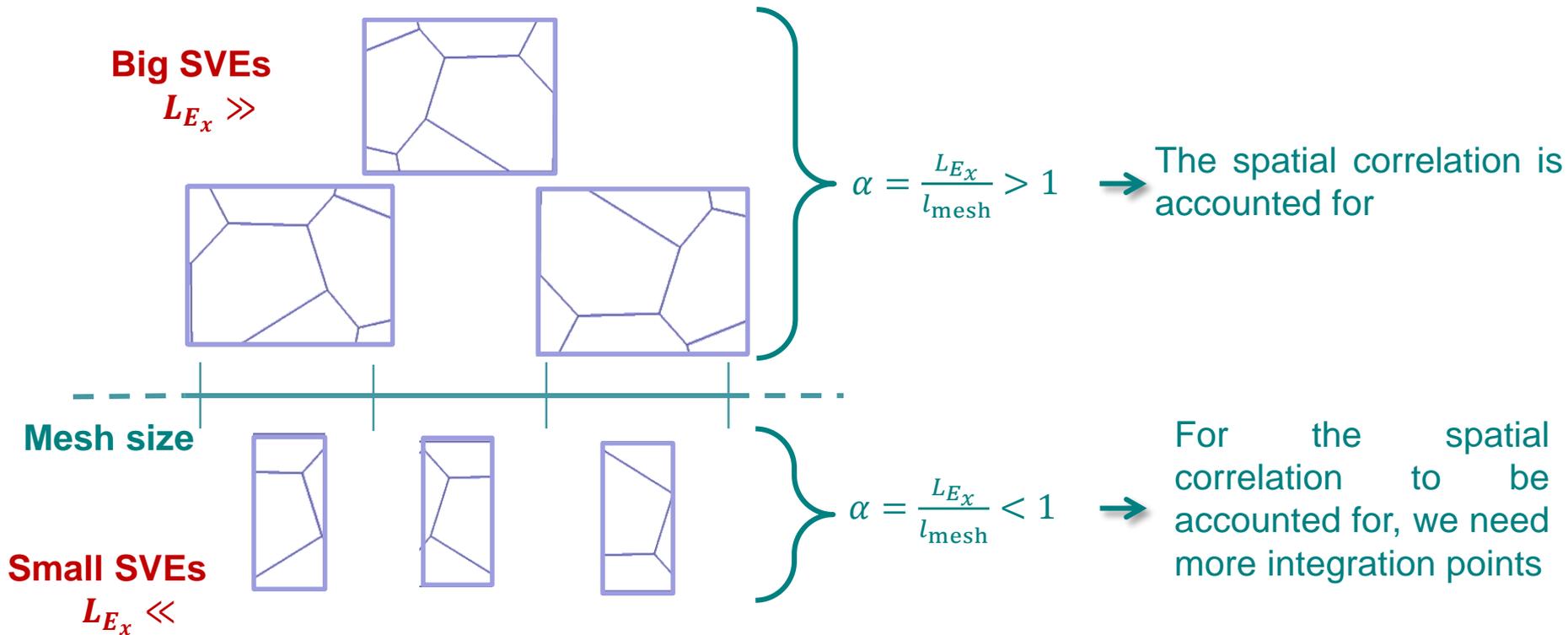
Fine macro-mesh



From the micro-scale to the meso-scale

- Need for a meso-scale random field (3)

- Effect of the ratio $\alpha = \frac{L_{Ex}}{l_{mesh}}$ (Only one gauss point in one element)

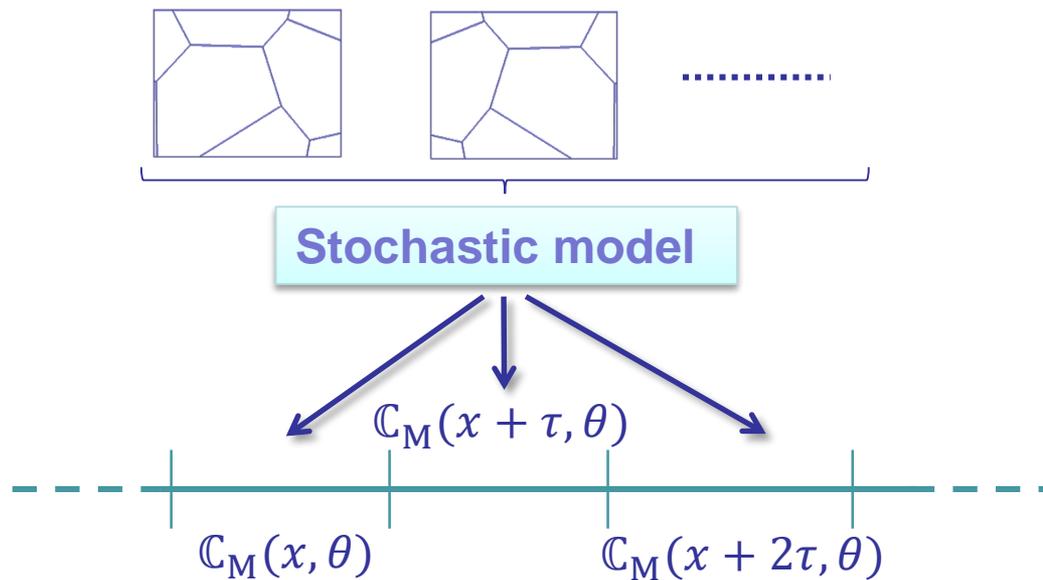


- For extreme values of α :
 - $\alpha \gg 1$: no more scale separation if $l_{SVE} \sim L_{macro}$
 - $\alpha \ll 1$: loss of microstructural details if $l_{SVE} \sim L_{micro}$

- From the micro-scale to the meso-scale
 - Thermo-mechanical homogenization
 - Definition of Stochastic Volume Elements (SVEs) & Stochastic homogenization
 - Need for a meso-scale random field
- **The meso-scale random field**
 - Definition of the thermo-mechanical meso-scale random field
 - Stochastic model of the random field: Spectral generator & non-Gaussian mapping
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 - From the meso-scale to the macro-scale

The meso-scale random field

- Use of the meso-scale distribution with stochastic (macro-scale) finite elements
 - Use of the meso-scale random field
 - Monte-Carlo simulations at the macro-scale
 - BUT we do not want to evaluate the random field from the stochastic homogenization for each simulation → Meso-scale random field from a generator
 - Need for a stochastic model of meso-scale elasticity tensors



The meso-scale random field

- Definition of the thermo-mechanical meso-scale random field

- Elasticity tensor $\mathbb{C}_M(x, \theta)$ (matrix form \mathbf{C}_M) & thermal conductivity κ_M are bounded
 - Ensure existence of their inverse
 - Define lower bounds \mathbb{C}_L and κ_L such that

$$\left\{ \begin{array}{ll} \boldsymbol{\varepsilon} : (\mathbb{C}_M - \mathbb{C}_L) : \boldsymbol{\varepsilon} > 0 & \forall \boldsymbol{\varepsilon} \\ \nabla \vartheta \cdot (\boldsymbol{\kappa}_M - \boldsymbol{\kappa}_L) \cdot \nabla \vartheta > 0 & \forall \nabla \vartheta \end{array} \right.$$

- Use a Cholesky decomposition when semi-positive definite matrices are required

$$\left\{ \begin{array}{l} \mathbf{C}_M(x, \theta) = \mathbf{C}_L + (\bar{\mathbf{A}} + \mathcal{A}'(x, \theta))^T (\bar{\mathbf{A}} + \mathcal{A}'(x, \theta)) \\ \boldsymbol{\kappa}_M(x, \theta) = \boldsymbol{\kappa}_L + (\bar{\mathbf{B}} + \mathcal{B}'(x, \theta))^T (\bar{\mathbf{B}} + \mathcal{B}'(x, \theta)) \\ \alpha_{M,ij}(x, \theta) = \bar{\nu}^{(t)} + \nu'^{(t)}(x, \theta) \end{array} \right.$$

- We define the homogenous zero-mean random field $\mathcal{V}'(x, \theta)$, with as entries

- Elasticity tensor $\mathcal{A}'(x, \theta) \Rightarrow \nu'^{(1)} \dots \nu'^{(21)}$,
- Heat conductivity tensor $\mathcal{B}'(x, \theta) \Rightarrow \nu'^{(22)} \dots \nu'^{(27)}$
- Thermal expansion tensors $\nu'^{(t)} \Rightarrow \nu'^{(28)} \dots \nu'^{(33)}$

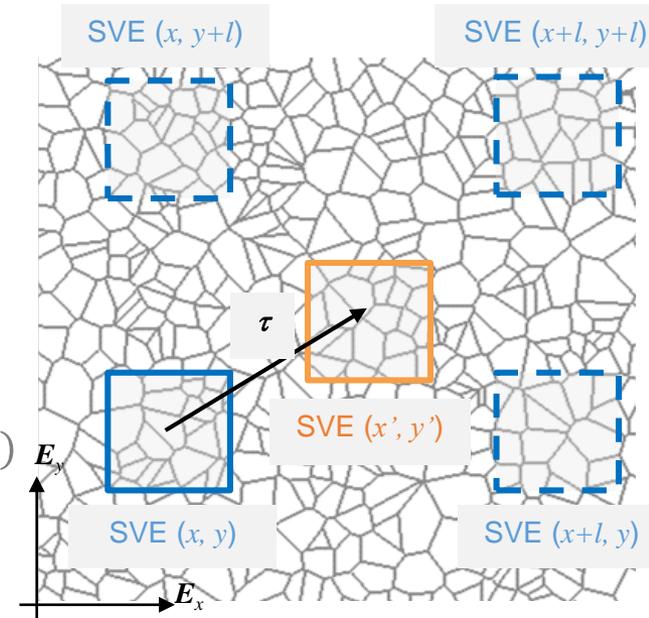
The meso-scale random field

- Characterization of the meso-scale random field

- Generate large tessellation realizations
- For each tessellation realization
 - Extract SVEs centered on $\mathbf{x} + \boldsymbol{\tau}$
 - For each SVE evaluate $\mathbb{C}_M(\mathbf{x} + \boldsymbol{\tau}), \kappa_M(\mathbf{x} + \boldsymbol{\tau}), \alpha_M(\mathbf{x} + \boldsymbol{\tau})$
- From the set of realizations $\mathbb{C}_M(\mathbf{x}, \boldsymbol{\theta}), \kappa_M(\mathbf{x}, \boldsymbol{\theta}), \alpha_M(\mathbf{x}, \boldsymbol{\theta})$
 - Evaluate the bounds \mathbb{C}_L and κ_L
 - Apply the Cholesky decomposition $\Rightarrow \mathcal{A}'(\mathbf{x}, \boldsymbol{\theta}), \mathcal{B}'(\mathbf{x}, \boldsymbol{\theta})$
 - Fill the 33 entries of the zero-mean homogenous field $\boldsymbol{\nu}'(\mathbf{x}, \boldsymbol{\theta})$
- Compute the auto-/cross-correlation matrix

$$R_{\boldsymbol{\nu}'}^{(rs)}(\boldsymbol{\tau}) = \frac{\mathbb{E}[\boldsymbol{\nu}'^{(r)}(\mathbf{x})\boldsymbol{\nu}'^{(s)}(\mathbf{x} + \boldsymbol{\tau})]}{\sqrt{\mathbb{E}[(\boldsymbol{\nu}'^{(r)})^2]\mathbb{E}[(\boldsymbol{\nu}'^{(s)})^2]}}$$

- Generate zero-mean random field $\boldsymbol{\nu}'(\mathbf{x}, \boldsymbol{\theta})$
 - Spectral generator & non-Gaussian mapping



The meso-scale random field

- Stochastic model of the meso-scale random field: Spectral generator*

- Start from the auto-/cross-covariance matrix

$$\tilde{R}_{\mathbf{v}'}^{(rs)}(\boldsymbol{\tau}) = \sigma_{\mathbf{v}'^{(r)}} \sigma_{\mathbf{v}'^{(s)}} R_{\mathbf{v}'}^{(rs)}(\boldsymbol{\tau}) = \mathbb{E} \left[\left(\mathbf{v}'^{(r)}(\mathbf{x}) - \mathbb{E}(\mathbf{v}'^{(r)}) \right) \left(\mathbf{v}'^{(s)}(\mathbf{x} + \boldsymbol{\tau}) - \mathbb{E}(\mathbf{v}'^{(s)}) \right) \right]$$

- Evaluate the spectral density matrix from the periodized zero-padded matrix $\tilde{R}_{\mathbf{v}'}^P(\boldsymbol{\tau})$

$$\mathbf{S}_{\mathbf{v}'}^{(rs)}[\boldsymbol{\omega}^{(m)}] = \sum_n \tilde{R}_{\mathbf{v}'}^P{}^{(rs)}[\boldsymbol{\tau}^{(n)}] e^{-2\pi i \boldsymbol{\tau}^{(n)} \cdot \boldsymbol{\omega}^{(m)}} \quad \& \quad \mathbf{S}_{\mathbf{v}'}[\boldsymbol{\omega}^{(m)}] = \mathbf{H}_{\mathbf{v}'}[\boldsymbol{\omega}^{(m)}] \mathbf{H}_{\mathbf{v}'}^*[\boldsymbol{\omega}^{(m)}]$$

- $\boldsymbol{\omega}$ gathers the discrete frequencies
- $\boldsymbol{\tau}$ gathers the discrete spatial locations

- Generate a Gaussian random field $\mathbf{v}'(\mathbf{x}, \boldsymbol{\theta})$

$$\mathbf{v}'^{(r)}(\mathbf{x}, \boldsymbol{\theta}) = \sqrt{2\Delta\omega} \Re \left(\sum_s \sum_m \mathbf{H}_{\mathbf{v}'}^{(rs)}[\boldsymbol{\omega}^{(m)}] \eta^{(s,m)} e^{2\pi i (\mathbf{x} \cdot \boldsymbol{\omega}^{(m)} + \boldsymbol{\theta}^{(s,m)})} \right)$$

- $\boldsymbol{\eta}$ and $\boldsymbol{\theta}$ are independent random variables

- Quid if a non-Gaussian distribution is sought?

*Shinozuka, M., Deodatis, G., 1988

The meso-scale random field

- Stochastic model of the meso-scale random field: non-Gaussian mapping*

- Start from micro-sampling of the stochastic homogenization

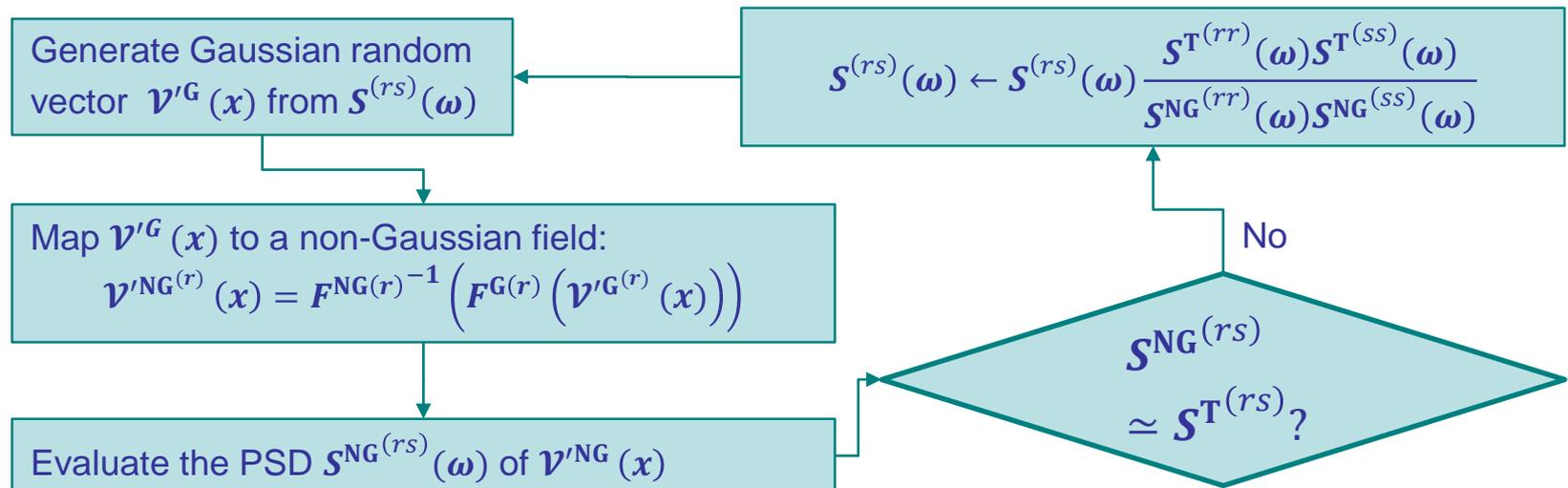
- The continuous form of the targeted PSD function

$$\mathcal{S}^{\text{T}(rs)}(\omega) = \Delta\tau \mathcal{S}_{\mathcal{V}'}^{(rs)}[\omega^{(m)}] = \Delta\tau \sum_n \tilde{R}_{\mathcal{V}'}^{\text{P}(rs)}[\boldsymbol{\tau}^{(n)}] e^{-2\pi i \boldsymbol{\tau}^{(n)} \cdot \omega^{(m)}}$$

- The targeted marginal distribution density function $F^{\text{NG}(r)}$ of the random variable $\mathcal{V}'^{(r)}$

- A marginal Gaussian distribution $F^{\text{G}(r)}$ of zero-mean and targeted variance $\sigma_{\mathcal{V}'^{(r)}}$

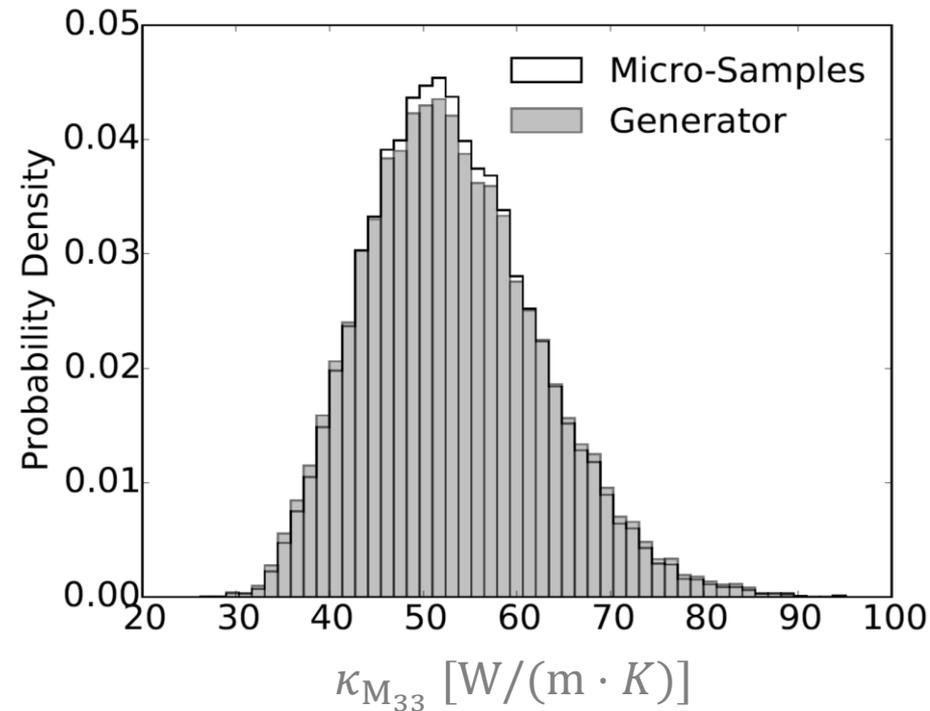
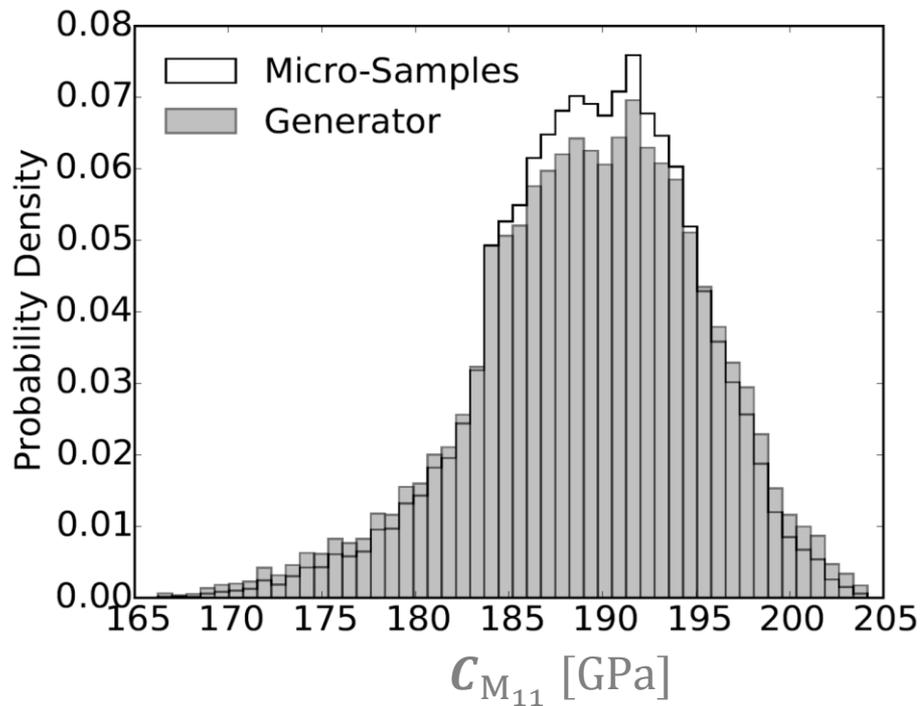
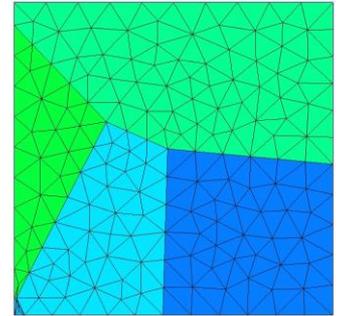
- Iterate



*Deodatis, G., Micaletti, R., 2001

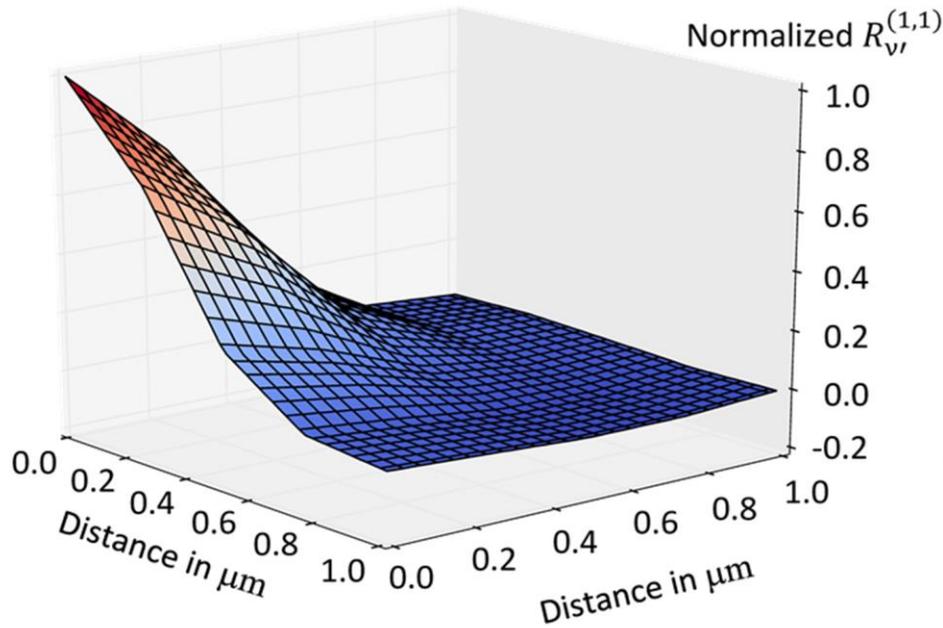
The meso-scale random field

- Polysilicon film deposited at 610 °C
 - SVE size of $0.5 \times 0.5 \mu\text{m}^2$
 - Comparison between micro-samples and generated field PDFs

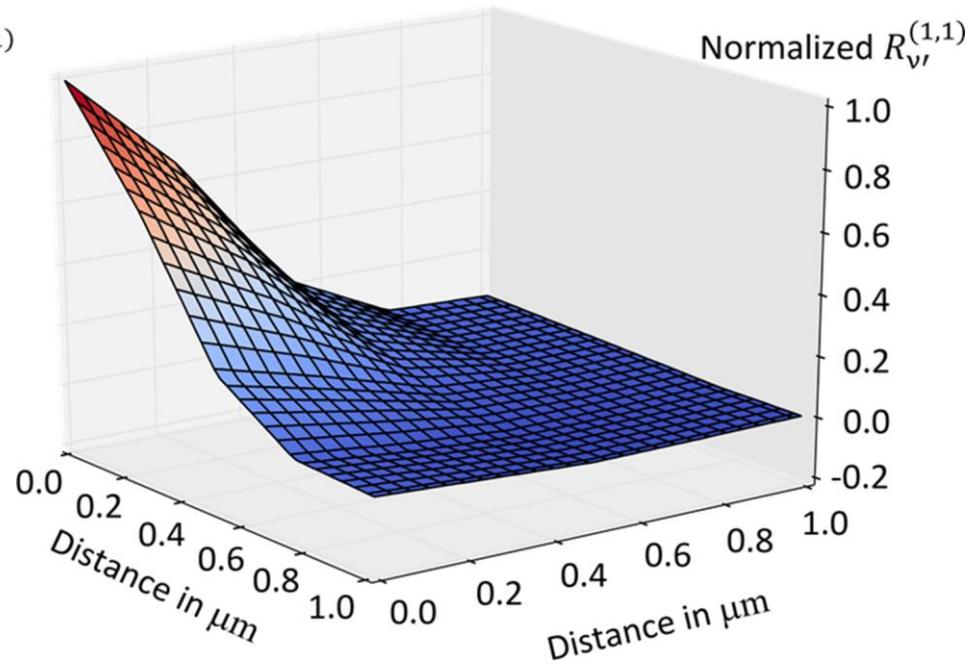


The meso-scale random field

- Polysilicon film deposited at 610 °C (2)
 - Comparison between micro-samples and generated field cross-correlations



Micro-Samples

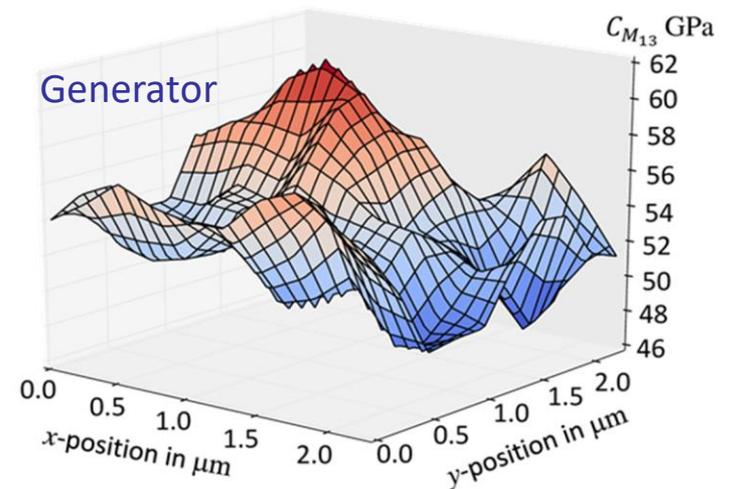
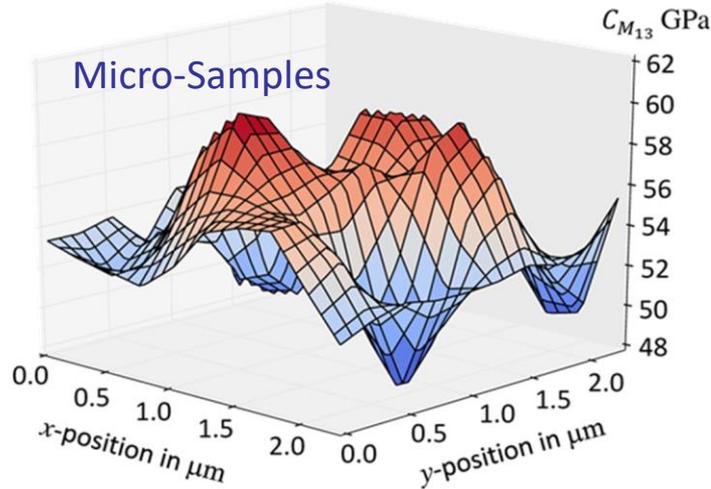
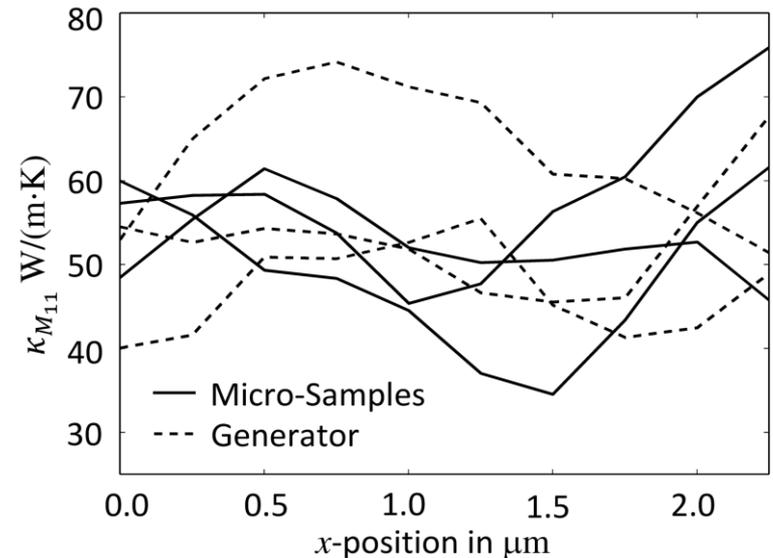
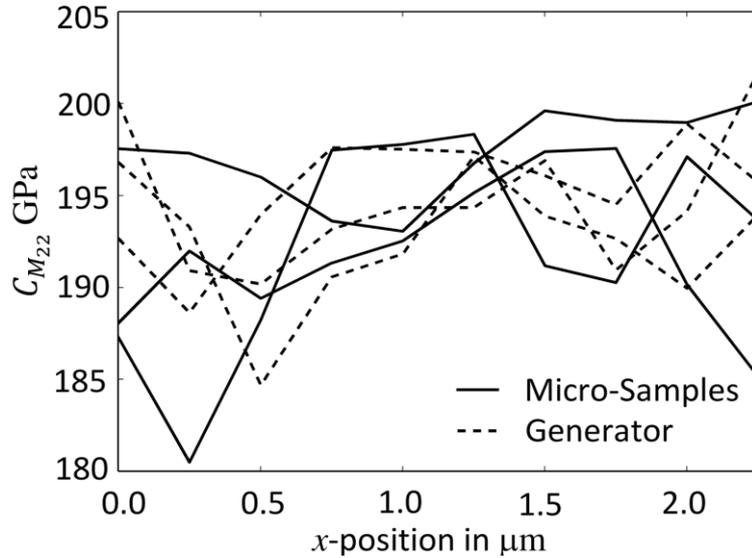


Generator

The meso-scale random field

- Polysilicon film deposited at 610 °C (3)

- Comparison between micro-samples and generated random field realizations



- From the micro-scale to the meso-scale
 - Thermo-mechanical homogenization
 - Definition of Stochastic Volume Elements (SVEs) & Stochastic homogenization
 - Need for a meso-scale random field
- The meso-scale random field
 - Definition of the thermo-mechanical meso-scale random field
 - Stochastic model of the random field: Spectral generator & non-Gaussian mapping
- **From the meso-scale to the macro-scale**
 - 3-Scale approach verification
 - Application to extract the quality factor
- Accounting for roughness effect
 - From the micro-scale to the meso-scale
 - The meso-scale random field
 - From the meso-scale to the macro-scale

From the meso-scale to the macro-scale

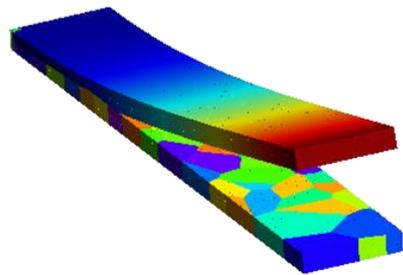
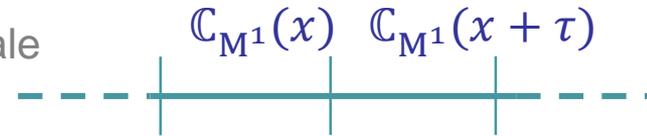
- 3-Scale approach verification with direct Monte-Carlo simulations

- Use of the meso-scale random field

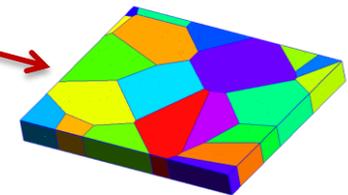
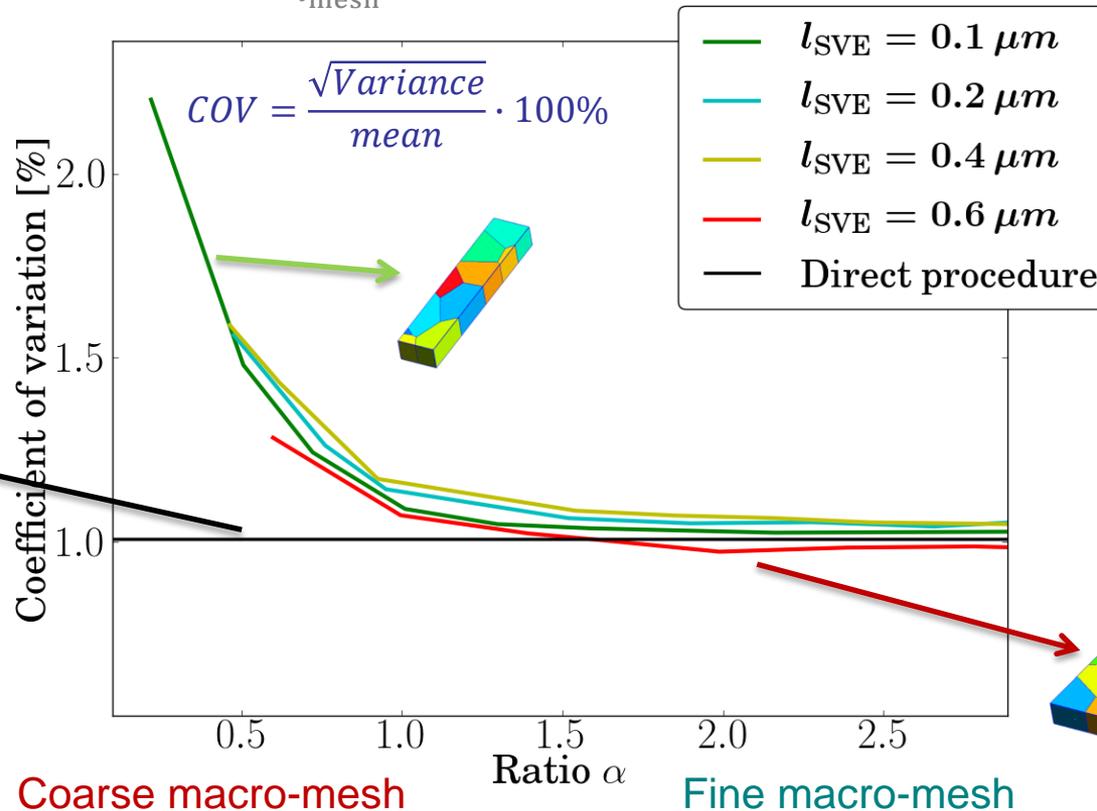
→ Monte-Carlo simulations at the macro-scale

- Macro-scale beam elements of size l_{mesh}

- Convergence in terms of $\alpha = \frac{l_{Ex}}{l_{\text{mesh}}}$

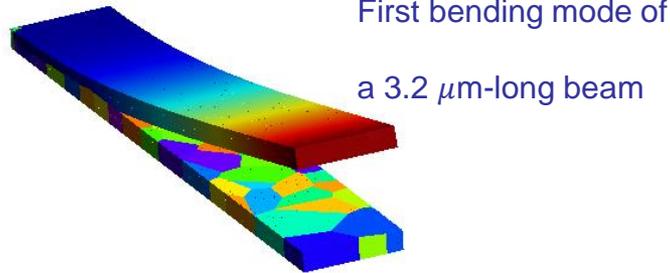


First bending mode of a 3.2 μm -long beam

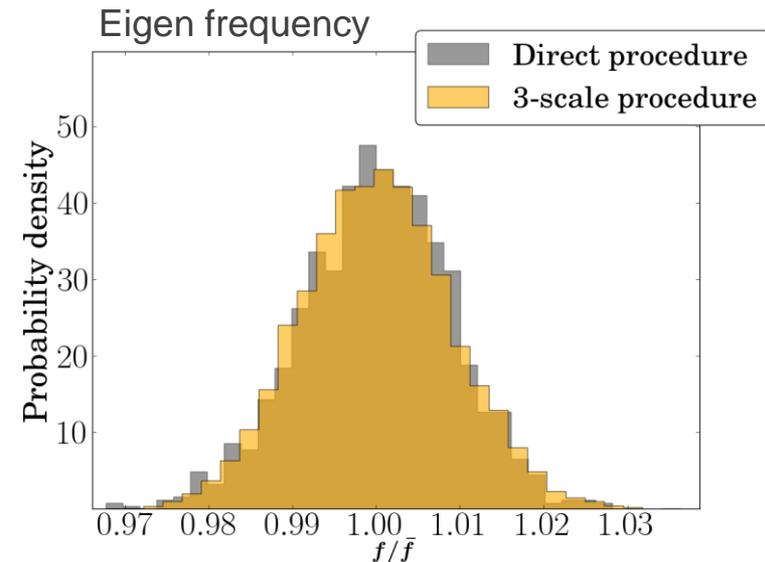
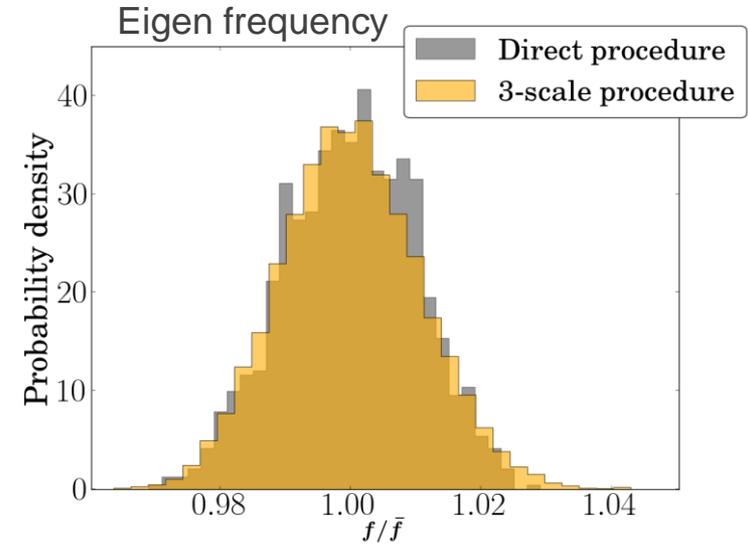
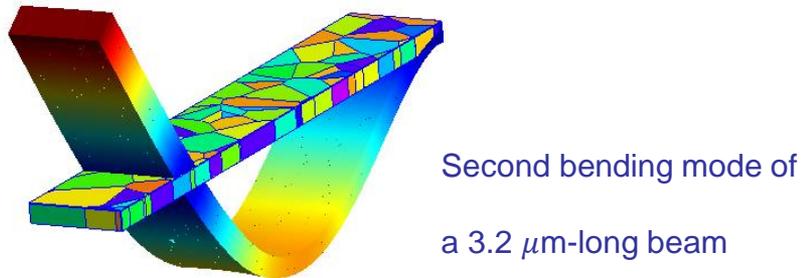


From the meso-scale to the macro-scale

- 3-Scale approach verification ($\alpha \sim 2$) with direct Monte-Carlo simulations
 - First bending mode



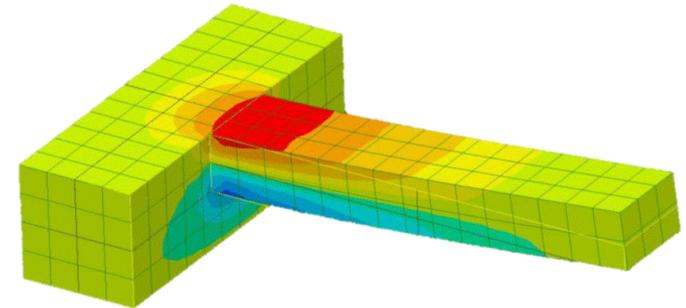
- Second bending mode



- Quality factor

- Micro-resonators

- Temperature changes with compression/traction
 - Energy dissipation



- Eigen values problem

- Governing equations

$$\begin{bmatrix} \mathbf{M} & \mathbf{0} \\ \mathbf{0} & \mathbf{0} \end{bmatrix} \begin{bmatrix} \ddot{\mathbf{u}} \\ \ddot{\boldsymbol{\vartheta}} \end{bmatrix} + \begin{bmatrix} \mathbf{0} & \mathbf{0} \\ \mathbf{D}_{u\vartheta}(\boldsymbol{\theta}) & \mathbf{D}_{\vartheta\vartheta} \end{bmatrix} \begin{bmatrix} \dot{\mathbf{u}} \\ \dot{\boldsymbol{\vartheta}} \end{bmatrix} + \begin{bmatrix} \mathbf{K}_{uu}(\boldsymbol{\theta}) & \mathbf{K}_{u\vartheta}(\boldsymbol{\theta}) \\ \mathbf{0} & \mathbf{K}_{\vartheta\vartheta}(\boldsymbol{\theta}) \end{bmatrix} \begin{bmatrix} \mathbf{u} \\ \boldsymbol{\vartheta} \end{bmatrix} = \begin{bmatrix} \mathbf{F}_u \\ \mathbf{F}_\vartheta \end{bmatrix}$$

- Free vibrating problem

$$\begin{bmatrix} \mathbf{u}(t) \\ \boldsymbol{\vartheta}(t) \end{bmatrix} = \begin{bmatrix} \mathbf{u}_0 \\ \boldsymbol{\vartheta}_0 \end{bmatrix} e^{i\omega t}$$

$$\hookrightarrow \begin{bmatrix} -\mathbf{K}_{uu}(\boldsymbol{\theta}) & -\mathbf{K}_{u\vartheta}(\boldsymbol{\theta}) & \mathbf{0} \\ \mathbf{0} & -\mathbf{K}_{\vartheta\vartheta}(\boldsymbol{\theta}) & \mathbf{0} \\ \mathbf{0} & \mathbf{0} & \mathbf{I} \end{bmatrix} \begin{bmatrix} \mathbf{u} \\ \boldsymbol{\vartheta} \\ \dot{\mathbf{u}} \end{bmatrix} = i\omega \begin{bmatrix} \mathbf{0} & \mathbf{0} & \mathbf{M} \\ \mathbf{D}_{\vartheta u}(\boldsymbol{\theta}) & \mathbf{D}_{\vartheta\vartheta} & \mathbf{0} \\ \mathbf{I} & \mathbf{0} & \mathbf{0} \end{bmatrix} \begin{bmatrix} \mathbf{u} \\ \boldsymbol{\vartheta} \\ \dot{\mathbf{u}} \end{bmatrix}$$

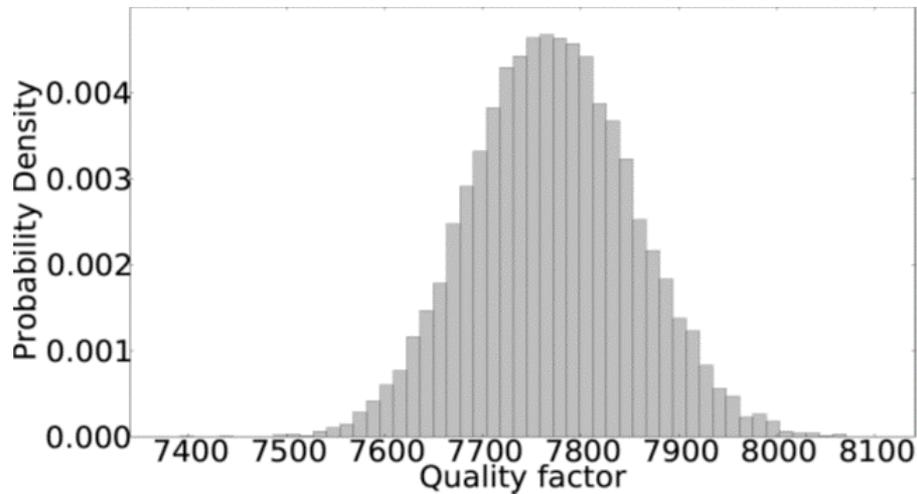
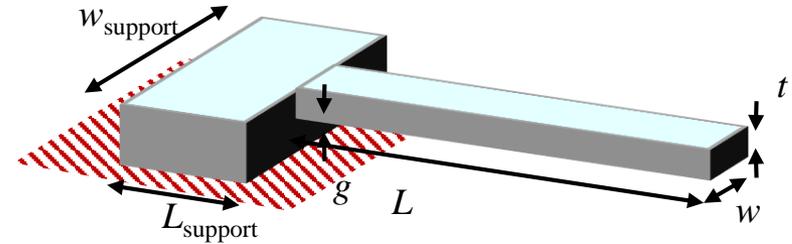
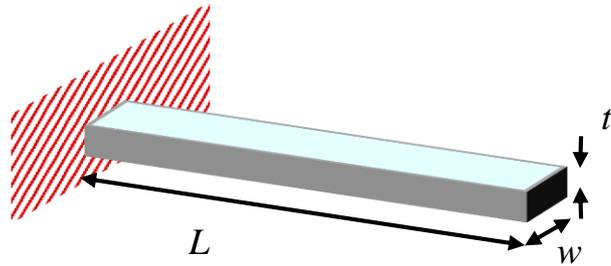
- Quality factor

- From the dissipated energy per cycle

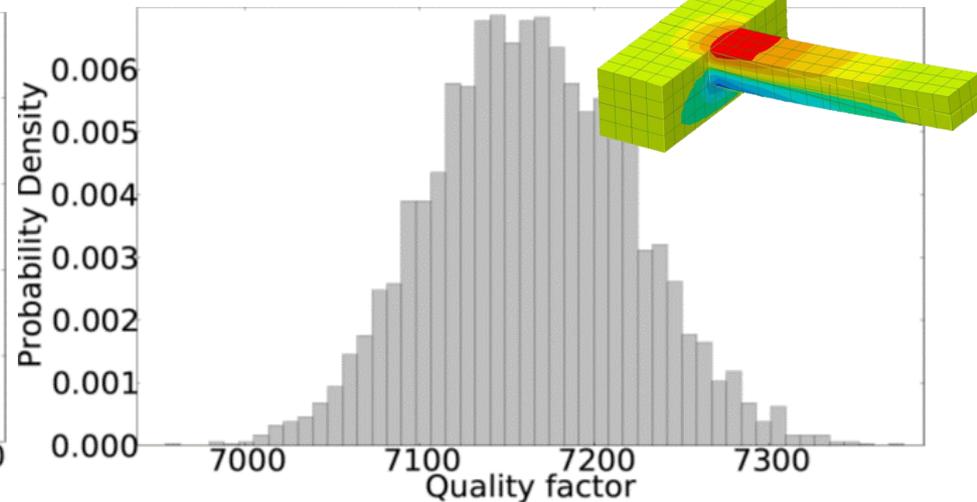
- $$Q^{-1} = \frac{2|\Im\omega|}{\sqrt{(\Re\omega)^2 + (\Im\omega)^2}}$$

From the meso-scale to the macro-scale

- Application of the 3-Scale method to extract the quality factor distribution
 - 3D models readily available
 - The effect of the anchor can be studied



$15 \times 3 \times 2 \mu\text{m}^3$ -beam,
deposited at $610 \text{ }^\circ\text{C}$

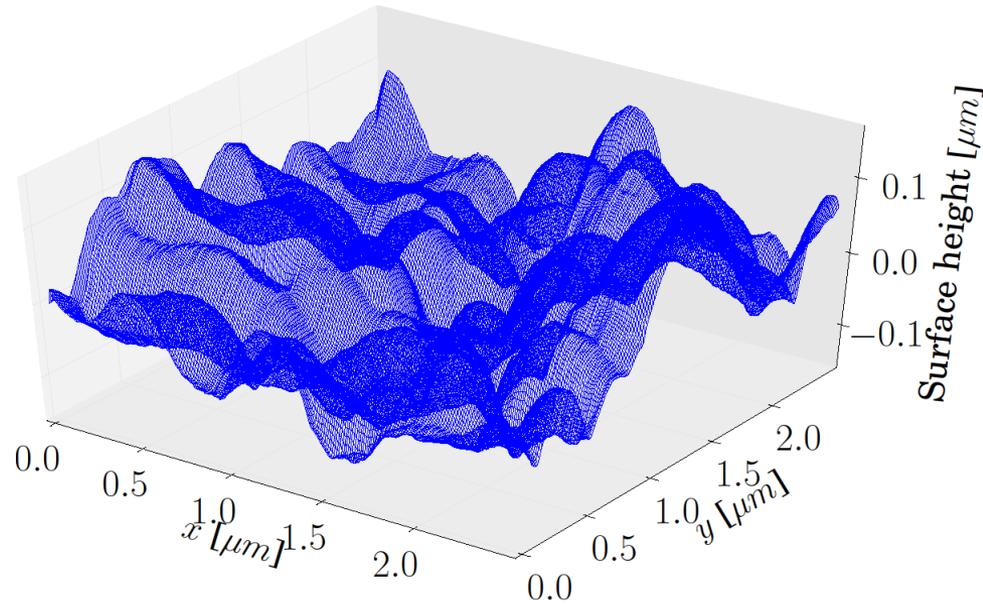


$15 \times 3 \times 2 \mu\text{m}^3$ -beam & anchor,
deposited at $610 \text{ }^\circ\text{C}$

- From the micro-scale to the meso-scale
 - Thermo-mechanical homogenization
 - Definition of Stochastic Volume Elements (SVEs) & Stochastic homogenization
 - Need for a meso-scale random field
- The meso-scale random field
 - Definition of the thermo-mechanical meso-scale random field
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- From the meso-scale to the macro-scale
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 - Application to extract the quality factor
- **Accounting for roughness effect**
 - From the micro-scale to the meso-scale
 - The meso-scale random field
 - From the meso-scale to the macro-scale

Accounting for roughness effect

- Surface topology: asperity distribution
 - Upper surface topology by AFM (Atomic Force Microscope) measurements on 2 μm -thick poly-silicon films



Deposition temperature [$^{\circ}\text{C}$]	580	610	630	650
Std deviation [nm]	35.6	60.3	90.7	88.3

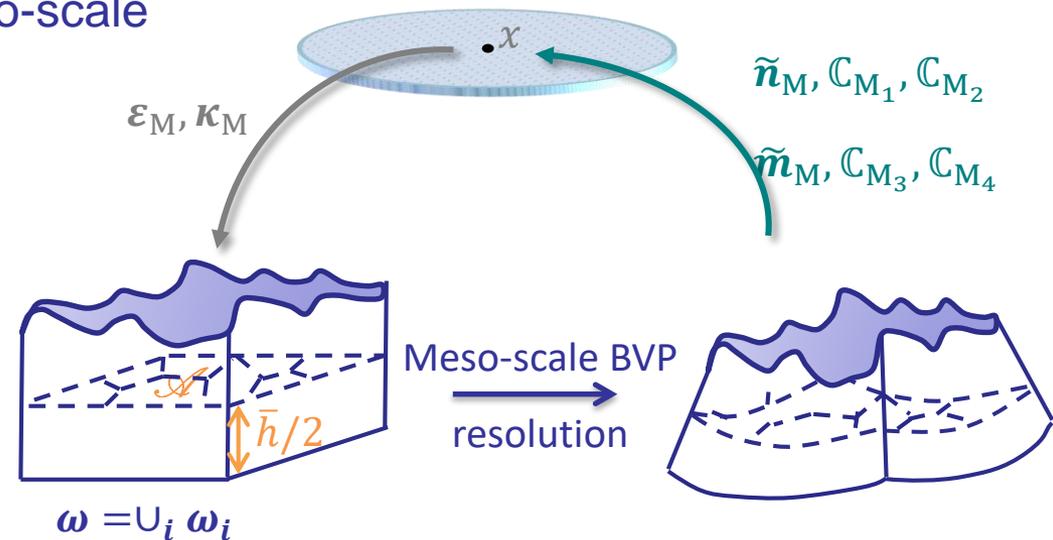
AFM data provided by IMT Bucharest, Rodica Voicu, Angela Baracu, Raluca Muller

Accounting for roughness effect

- From the micro-scale to the meso-scale

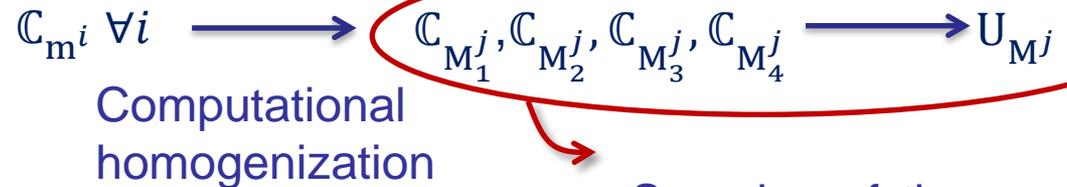
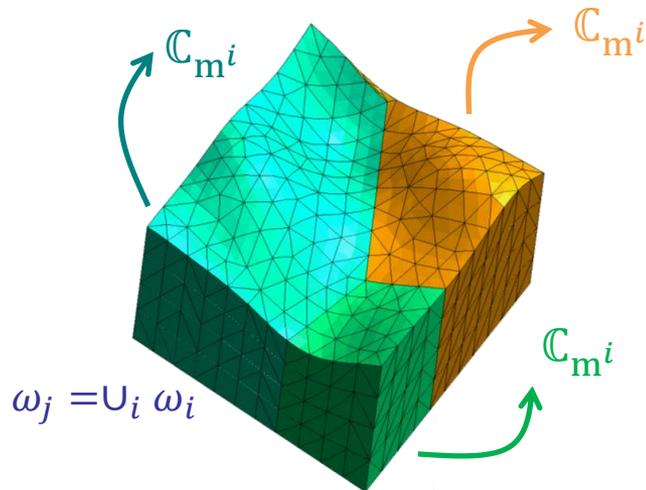
- Second-order homogenization

$$\begin{cases} \tilde{\mathbf{n}}_M = \mathbb{C}_{M_1} : \boldsymbol{\varepsilon}_M + \mathbb{C}_{M_2} : \boldsymbol{\kappa}_M \\ \tilde{\mathbf{m}}_M = \mathbb{C}_{M_3} : \boldsymbol{\varepsilon}_M + \mathbb{C}_{M_4} : \boldsymbol{\kappa}_M \end{cases}$$



- Stochastic homogenization

- Several SVE realizations
 - For each SVE $\boldsymbol{\omega}_j = U_i \boldsymbol{\omega}_i$
 - The density per unit area is now non-constant

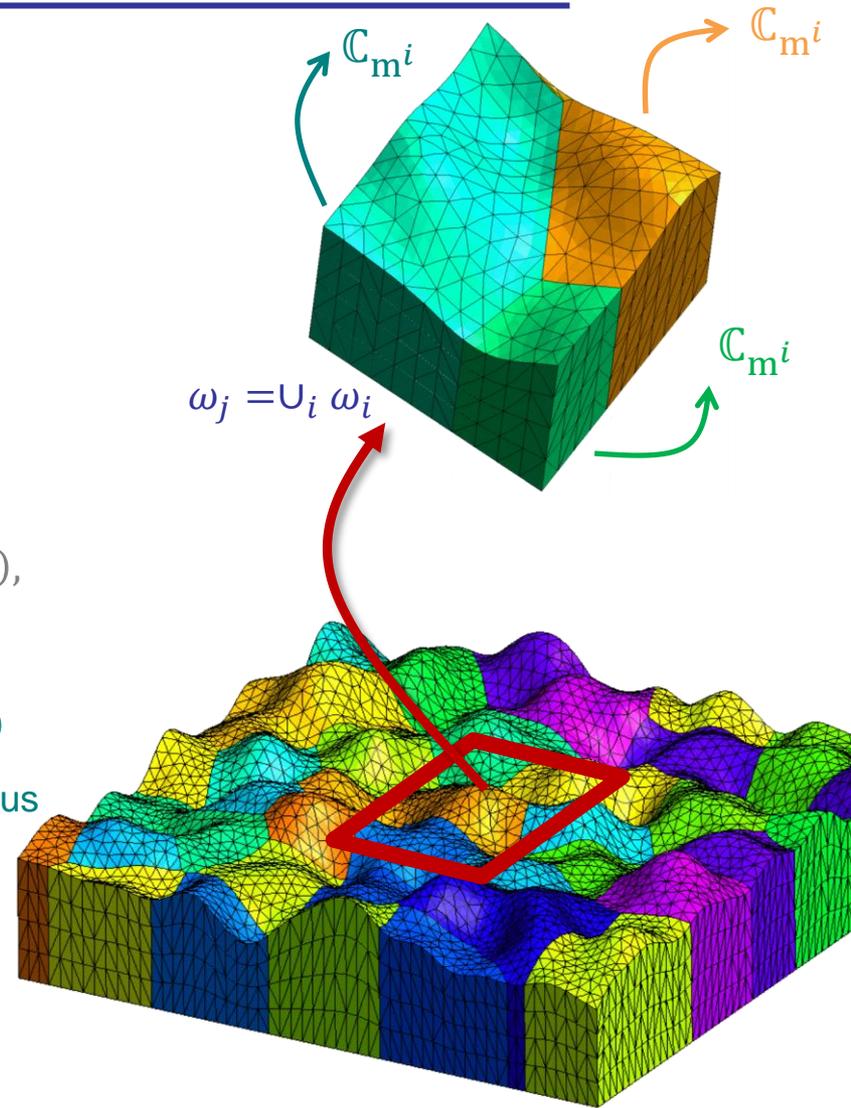


Samples of the meso-scale homogenized elasticity matrix U_M & density $\bar{\rho}_M$

Accounting for roughness effect

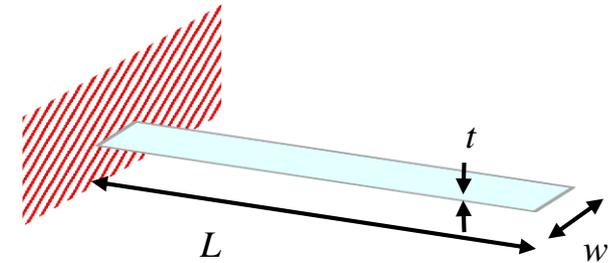
- The meso-scale random field
 - Generate large tessellation realizations
 - For each tessellation realization
 - Extract SVEs centred at $\mathbf{x} + \boldsymbol{\tau}$
 - For each SVE evaluate $U_M(\mathbf{x} + \boldsymbol{\tau}), \bar{\rho}_M(\mathbf{x} + \boldsymbol{\tau})$
 - From the set of realizations $U_M(\mathbf{x}, \boldsymbol{\theta}), \bar{\rho}_M(\mathbf{x}, \boldsymbol{\theta}),$
 - Evaluate the bounds \mathbf{U}_L and $\bar{\rho}_L$
 - Apply the Cholesky decomposition $\Rightarrow \mathcal{A}'(\mathbf{x}, \boldsymbol{\theta})$
 - Fill the 22 entries of the zero-mean homogenous field $\mathcal{V}'(\mathbf{x}, \boldsymbol{\theta})$
 - Compute the auto-/cross-correlation matrix

$$R_{\mathcal{V}'}^{(rs)}(\boldsymbol{\tau}) = \frac{\mathbb{E}[\mathcal{V}'^{(r)}(\mathbf{x})\mathcal{V}'^{(s)}(\mathbf{x} + \boldsymbol{\tau})]}{\sqrt{\mathbb{E}[(\mathcal{V}'^{(r)})^2]\mathbb{E}[(\mathcal{V}'^{(s)})^2]}}$$



Accounting for roughness effect

- From the meso-scale to the macro-scale
 - Cantilever of $8 \times 3 \times t \mu\text{m}^3$ deposited at 610°C



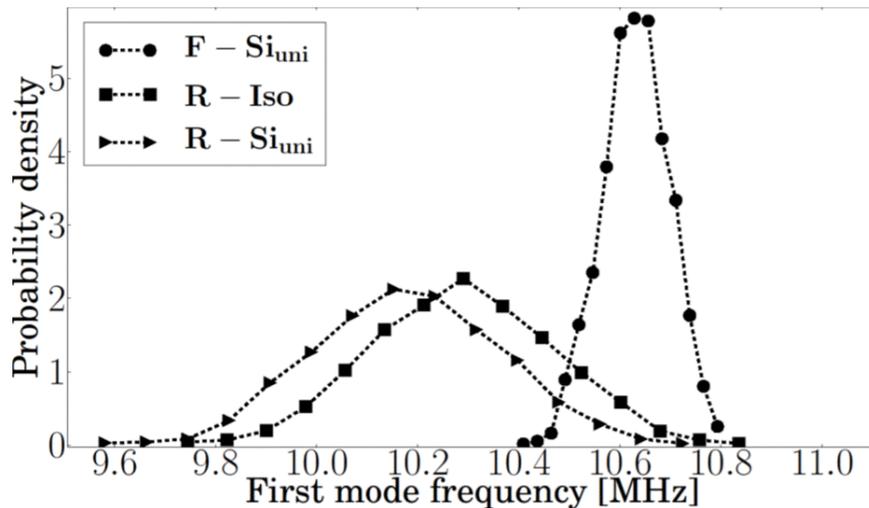
Flat SVEs (no roughness) - F

Rough SVEs (Polysilicon film deposited at 610°C) - R

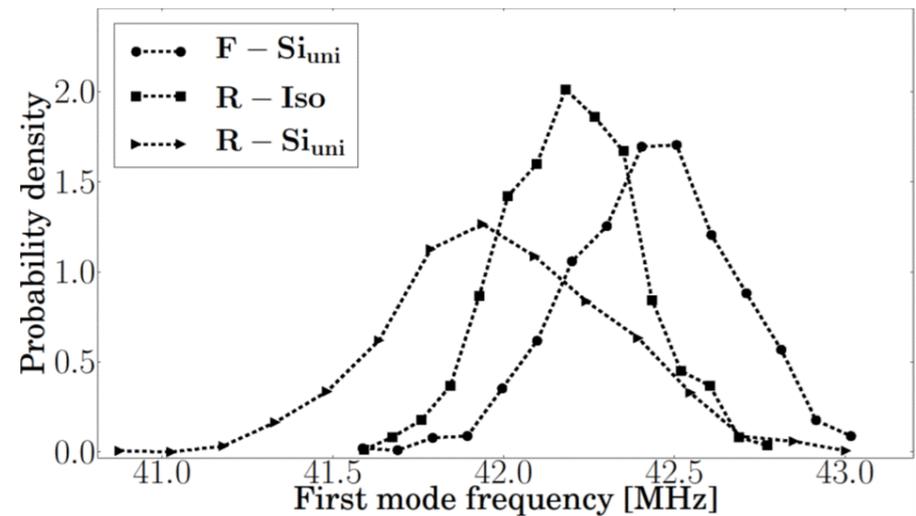
Grain orientation following XRD measurements – Si_{pref}

Grain orientation uniformly distributed – Si_{uni}

Reference isotropic material – Iso



Roughness effect is the most important for $8 \times 3 \times 0.5 \mu\text{m}^3$ cantilevers



Roughness effect is of same importance as orientation for $8 \times 3 \times 2 \mu\text{m}^3$ cantilevers

Conclusions & Perspectives

- Efficient stochastic multi-scale method
 - Micro-structure based on experimental measurements
 - Computational efficiency relies on the meso-scale random field generator
 - Used to study probabilistic behaviors

- Perspectives
 - Other material systems
 - Non-linear behaviors
 - Non-homogenous random fields

Thank you for your attention !

Thermo-mechanical problem

- Governing equations

- Thermo-mechanics

- Linear balance $\rho \ddot{\mathbf{u}} - \nabla \cdot \boldsymbol{\sigma} - \rho \mathbf{b} = 0$

- Clausius-Duhem inequality in terms of volume entropy rate $\dot{S} = -\frac{\nabla \cdot \mathbf{q}}{T}$

- Helmholtz free energy

$$\left\{ \begin{array}{l} \mathcal{F}(\boldsymbol{\varepsilon}, T) = \mathcal{F}_0(T) - \boldsymbol{\varepsilon} : \frac{\partial^2 \psi}{\partial \boldsymbol{\varepsilon} \partial \boldsymbol{\varepsilon}} : \boldsymbol{\alpha} (T - T_0) + \psi(\boldsymbol{\varepsilon}) \\ \boldsymbol{\sigma} = \left(\frac{\partial \mathcal{F}}{\partial \boldsymbol{\varepsilon}} \right)_T, \quad S = \left(\frac{\partial \mathcal{F}}{\partial T} \right)_\boldsymbol{\varepsilon} \quad \& \quad \left(\frac{\partial^2 \mathcal{F}_0}{\partial T \partial T} \right) = \rho C_v \end{array} \right.$$

- Strong form in terms of the displacements \mathbf{u} and temperature change ϑ (linear elasticity)

$$\hookrightarrow \left\{ \begin{array}{l} \rho \ddot{\mathbf{u}} - \nabla \cdot (\mathbb{C} : \dot{\boldsymbol{\varepsilon}} - \mathbb{C} : \boldsymbol{\alpha} \vartheta) - \rho \mathbf{b} = 0 \\ \rho C_v \dot{\vartheta} + T_0 \boldsymbol{\alpha} : \mathbb{C} : \dot{\boldsymbol{\varepsilon}} - \nabla \cdot (\boldsymbol{\kappa} \nabla \vartheta) = 0 \end{array} \right.$$

- Finite element discretization

$$\hookrightarrow \begin{bmatrix} \mathbf{M}(\rho) & \mathbf{0} \\ \mathbf{0} & \mathbf{0} \end{bmatrix} \begin{bmatrix} \ddot{\mathbf{u}} \\ \dot{\vartheta} \end{bmatrix} + \begin{bmatrix} \mathbf{0} & \mathbf{0} \\ \mathbf{D}_{\vartheta \mathbf{u}}(\boldsymbol{\alpha}, \mathbb{C}) & \mathbf{D}_{\vartheta \vartheta}(\rho C_v) \end{bmatrix} \begin{bmatrix} \dot{\mathbf{u}} \\ \dot{\vartheta} \end{bmatrix} + \begin{bmatrix} \mathbf{K}_{\mathbf{u}\mathbf{u}}(\mathbb{C}) & \mathbf{K}_{\mathbf{u}\vartheta}(\boldsymbol{\alpha}, \mathbb{C}) \\ \mathbf{0} & \mathbf{K}_{\vartheta\vartheta}(\boldsymbol{\kappa}) \end{bmatrix} \begin{bmatrix} \mathbf{u} \\ \vartheta \end{bmatrix} = \begin{bmatrix} \mathbf{F}_u \\ \mathbf{F}_\vartheta \end{bmatrix}$$

The meso-scale random field

- Stochastic model of the meso-scale random field: Spectral generator*

- Start from the auto-/cross-covariance matrix

$$\tilde{R}_{\mathbf{v}'}^{(rs)}(\boldsymbol{\tau}) = \sigma_{\mathbf{v}'^{(r)}} \sigma_{\mathbf{v}'^{(s)}} R_{\mathbf{v}'}^{(rs)}(\boldsymbol{\tau}) = \mathbb{E} \left[\left(\mathbf{v}'^{(r)}(\mathbf{x}) - \mathbb{E}(\mathbf{v}'^{(r)}) \right) \left(\mathbf{v}'^{(s)}(\mathbf{x} + \boldsymbol{\tau}) - \mathbb{E}(\mathbf{v}'^{(s)}) \right) \right]$$

- Evaluate the spectral density matrix from the periodized zero-padded matrix $\tilde{R}_{\mathbf{v}'}^P(\boldsymbol{\tau})$

$$\mathbf{S}_{\mathbf{v}'}^{(rs)}[\boldsymbol{\omega}^{(m)}] = \sum_n \tilde{R}_{\mathbf{v}'}^P{}^{(rs)}[\boldsymbol{\tau}^{(n)}] e^{-2\pi i \boldsymbol{\tau}^{(n)} \cdot \boldsymbol{\omega}^{(m)}} \quad \& \quad \mathbf{S}_{\mathbf{v}'}[\boldsymbol{\omega}^{(m)}] = \mathbf{H}_{\mathbf{v}'}[\boldsymbol{\omega}^{(m)}] \mathbf{H}_{\mathbf{v}'}^*[\boldsymbol{\omega}^{(m)}]$$

- $\boldsymbol{\omega}$ gathers the discrete frequencies
- $\boldsymbol{\tau}$ gathers the discrete spatial locations

- Generate a Gaussian random field $\mathbf{v}'(\mathbf{x}, \boldsymbol{\theta})$

$$\mathbf{v}'^{(r)}(\mathbf{x}, \boldsymbol{\theta}) = \sqrt{2\Delta\omega} \Re \left(\sum_s \sum_m \mathbf{H}_{\mathbf{v}'}^{(rs)}[\boldsymbol{\omega}^{(m)}] \eta^{(s,m)} e^{2\pi i (\mathbf{x} \cdot \boldsymbol{\omega}^{(m)} + \boldsymbol{\theta}^{(s,m)})} \right)$$

- $\boldsymbol{\eta}$ and $\boldsymbol{\theta}$ are independent random variables

- Quid if a non-Gaussian distribution is sought?

*Shinozuka, M., Deodatis, G., 1988

The meso-scale random field

- Stochastic model of the meso-scale random field: non-Gaussian mapping*

- Start from micro-sampling of the stochastic homogenization

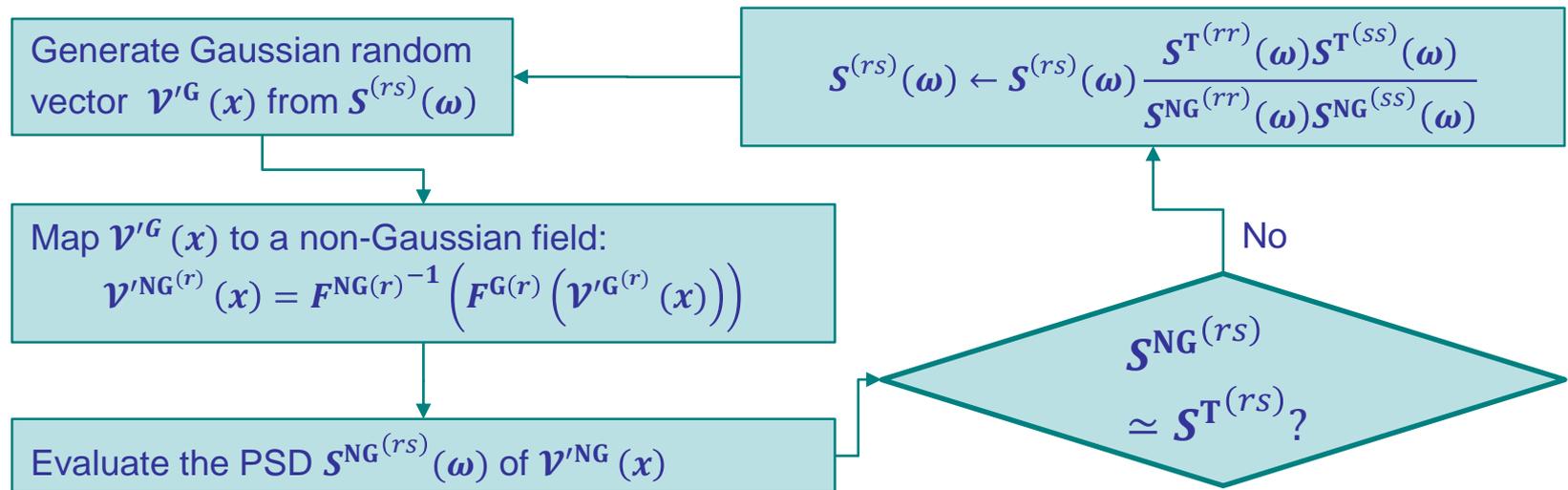
- The continuous form of the targeted PSD function

$$S^{T(rs)}(\omega) = \Delta\tau S_{\mathcal{V}'}^{(rs)}[\omega^{(m)}] = \Delta\tau \sum_n \tilde{R}_{\mathcal{V}'}^{P(rs)}[\tau^{(n)}] e^{-2\pi i \tau^{(n)} \cdot \omega^{(m)}}$$

- The targeted marginal distribution density function $F^{NG(r)}$ of the random variable $\mathcal{V}'^{(r)}$

- A marginal Gaussian distribution $F^{G(r)}$ of zero-mean and targeted variance $\sigma_{\mathcal{V}'^{(r)}}$

- Iterate



*Deodatis, G., Micaletti, R., 2001